

Checking new test sample from vertexing aspects

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ILD ana/soft meeting, 20th May 2020



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General Remarks

❖ Motivation

Validate new test samples by looking at variables related to vertexing

❖ Identical LCFIPlus used for comparison

To compare samples themselves

Differences are expected to come from PFO parameters (if same beam spot constraint is used)

❖ Identical process used for comparison

$\mu\mu H$ process

Samples Used

New test sample
250GeV, w/ IP smearing

DBD sample
250GeV, w/o IP smearing

IDR sample
500GeV, w/ IP smearing

❖ New test sample (250 GeV)

`rv02-01.sv02-01.mILD_l5_o1_v02_nobg.E250-SetA.I401006.Pe2e2h.eL.pR.n000.d_dstm_14717_X.slcio`

❖ “DBD” sample (250 GeV, w/o IP smearing)

`rv01-16-p10_250.sv01-14-01-p00.mILD_o1_v05.E250-TDR_ws.I106479.Pe2e2h.eL.pR-X-DST.slcio`

Reprocess the sample with SetA beam spot constraint

❖ “IDR” sample (500 GeV, w/ IP smearing)

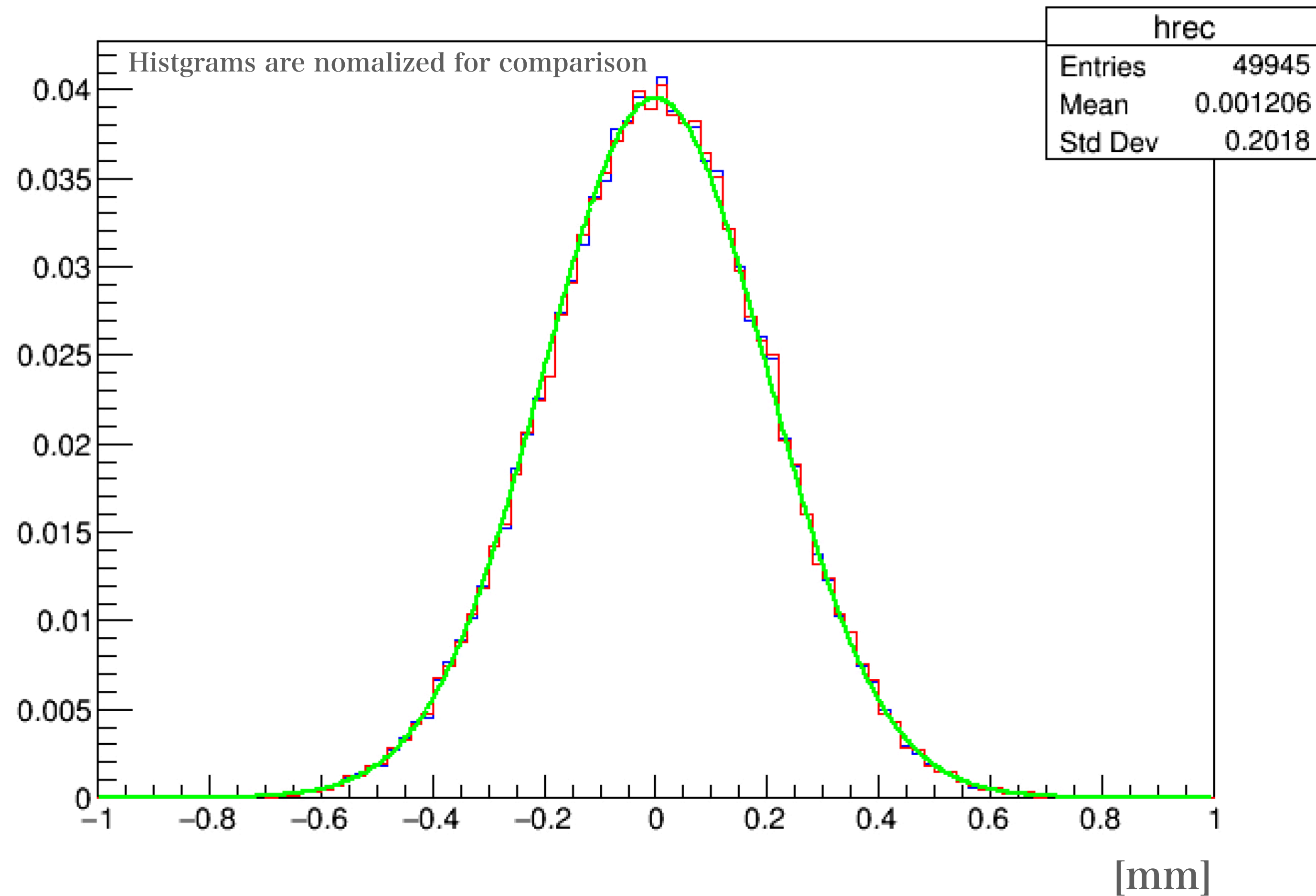
`rv02-00-01.sv02-00-01.mILD_l5_o1_v02.E500-TDR_ws.I106519.Pe2e2h.eL.pR.n001.d_dstm_10263_0.slcio`

Reprocess the sample with SetA beam spot constraint

Primary Vertex
Comparison between Reco and MC



Primary Vertex : z-position



New test sample,

Blue : Reconstructed

Red : MC

Green : Gaussian with sigma of beam spot constraint (202.e-3)

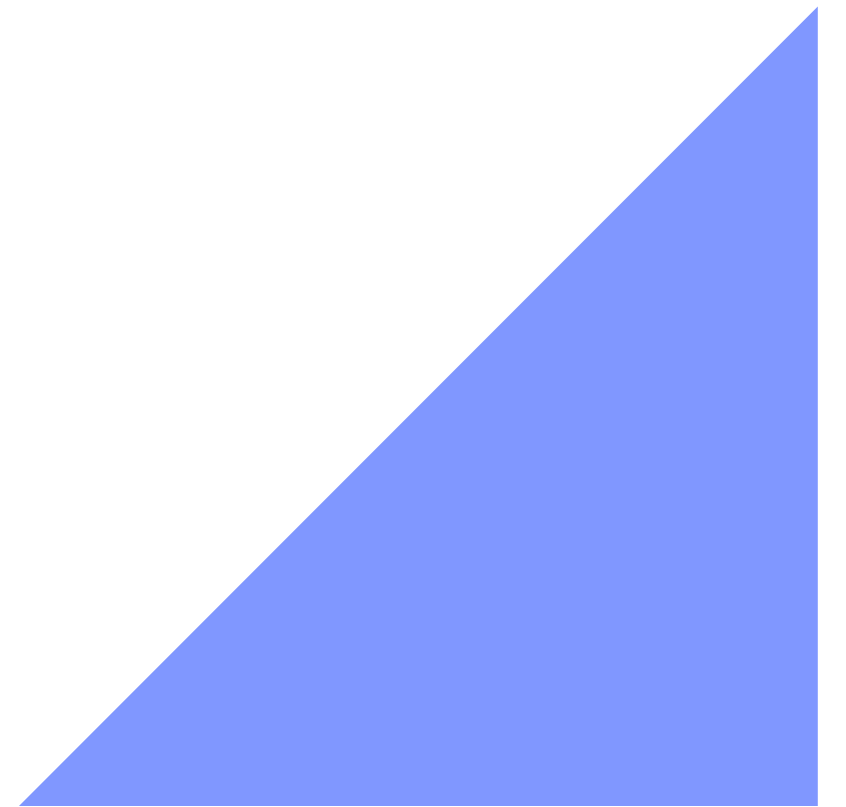
How we constrain vertex position?
A virtual point having central value of 0 and sigma of 202.e-3 is used in vertex fitting.

See backup for x and y.

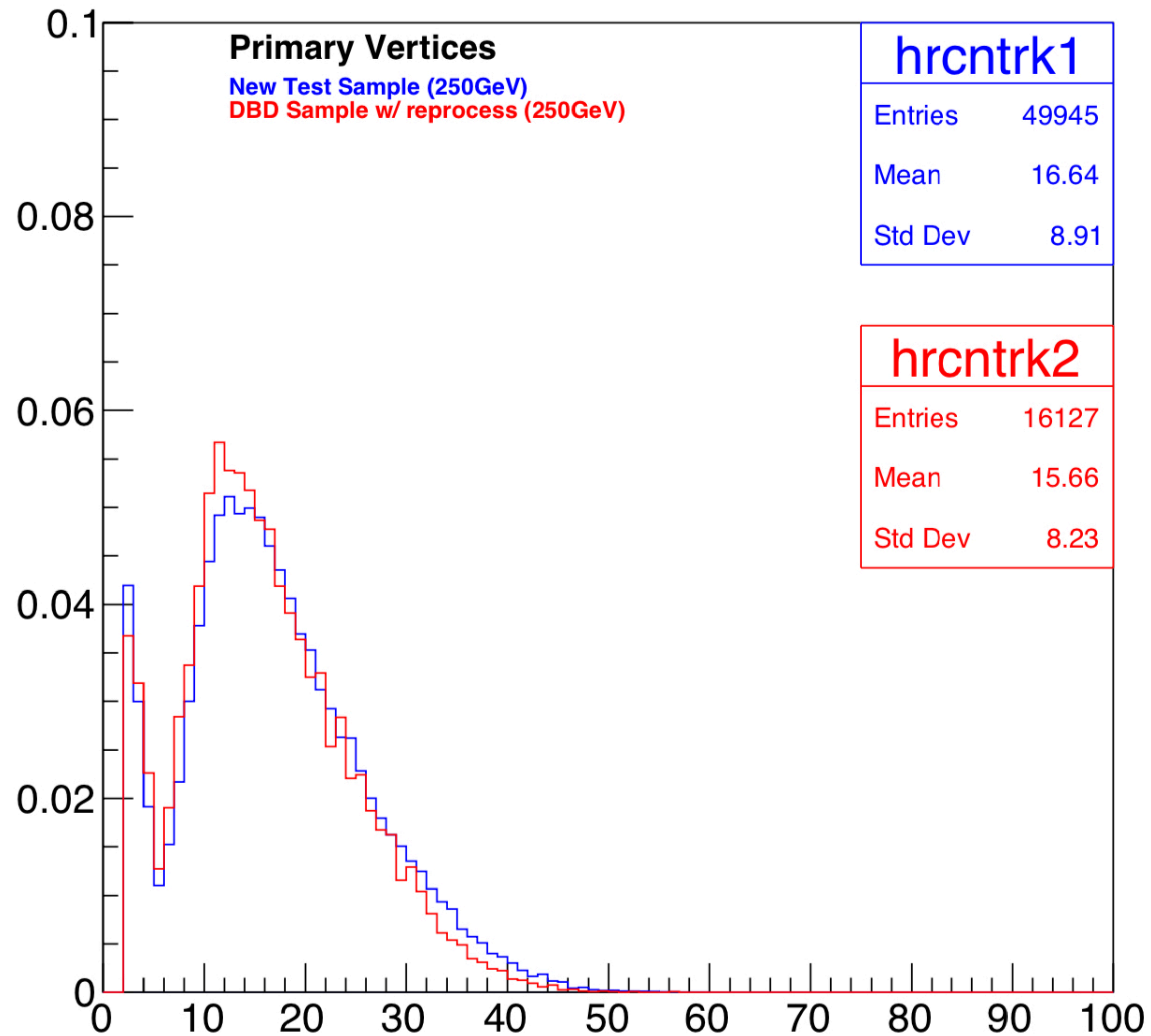
Reco and MC are consistent with beam spot constraint

Primary Vertex

Comparison between New test sample and “DBD” sample (250 GeV, w/o IP smearing)



Primary Vertex : # of tracks



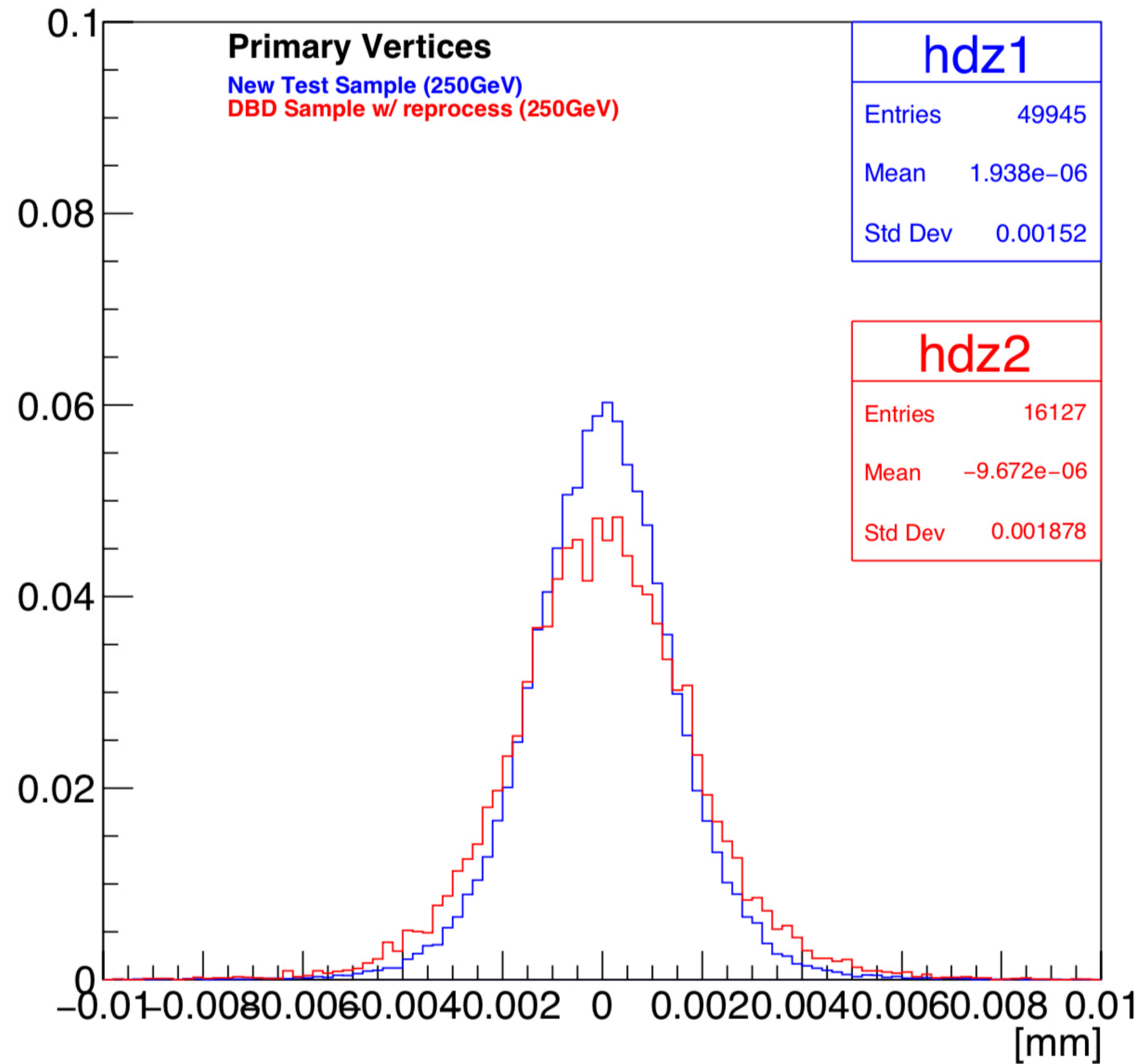
Blue : New test sample

Red : DBD sample w/ reprocess (250 GeV, w/
o IP smearing)

No clear difference

Primary Vertex : z-position residual

$$= (\text{Rec} - \text{MC})$$



Blue : New test sample

Red : DBD sample w/ reprocess (250 GeV, w/
o IP smearing)

See backup for x and y.

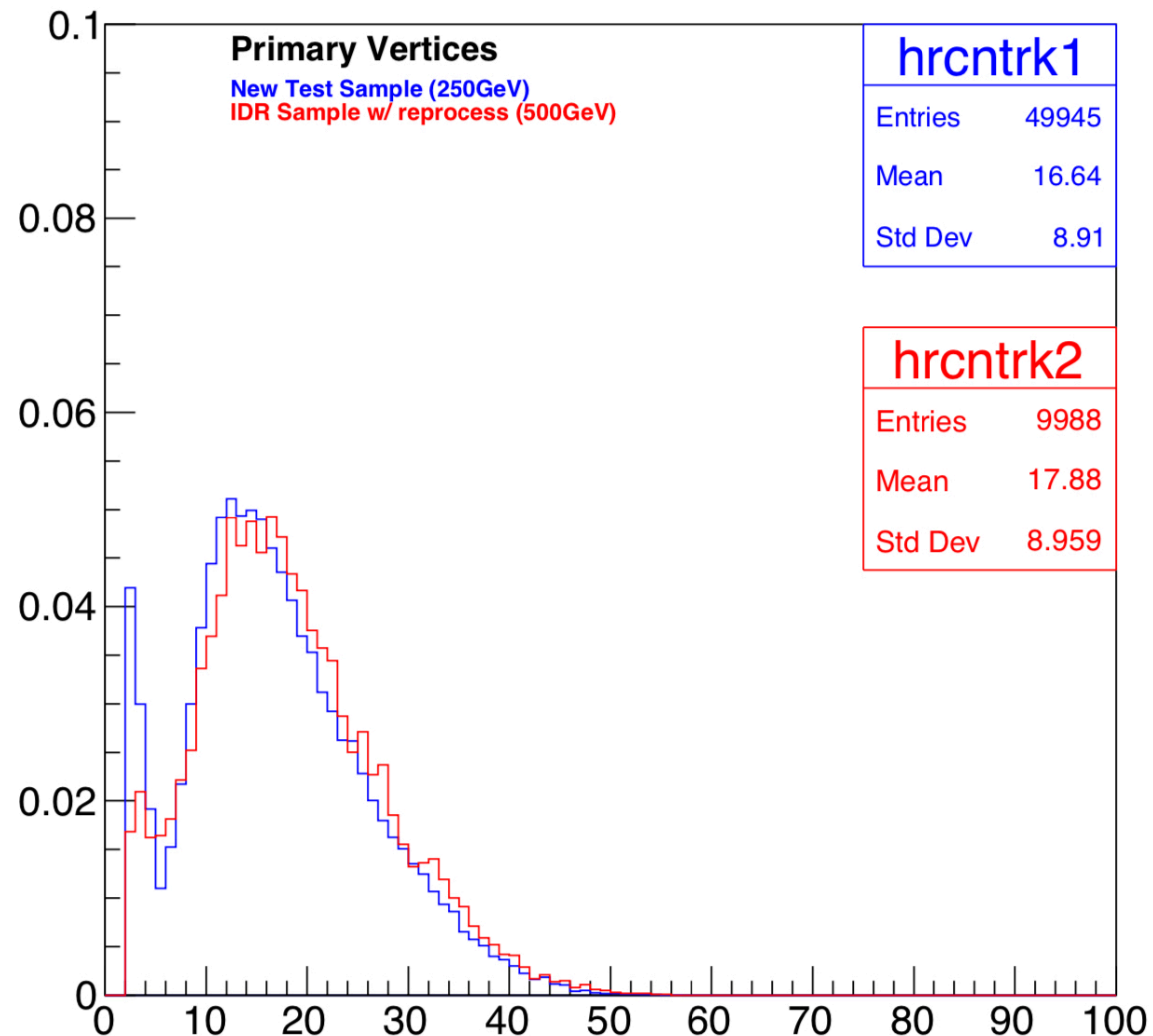
Looks slightly improved

Primary Vertex

Comparison between new test sample and “IDR” sample (500GeV, w/ IP smearing)



Primary Vertex : # of tracks



Blue : New test sample

Red : IDR sample w/ reprocess (500 GeV, w/ IP smearing)

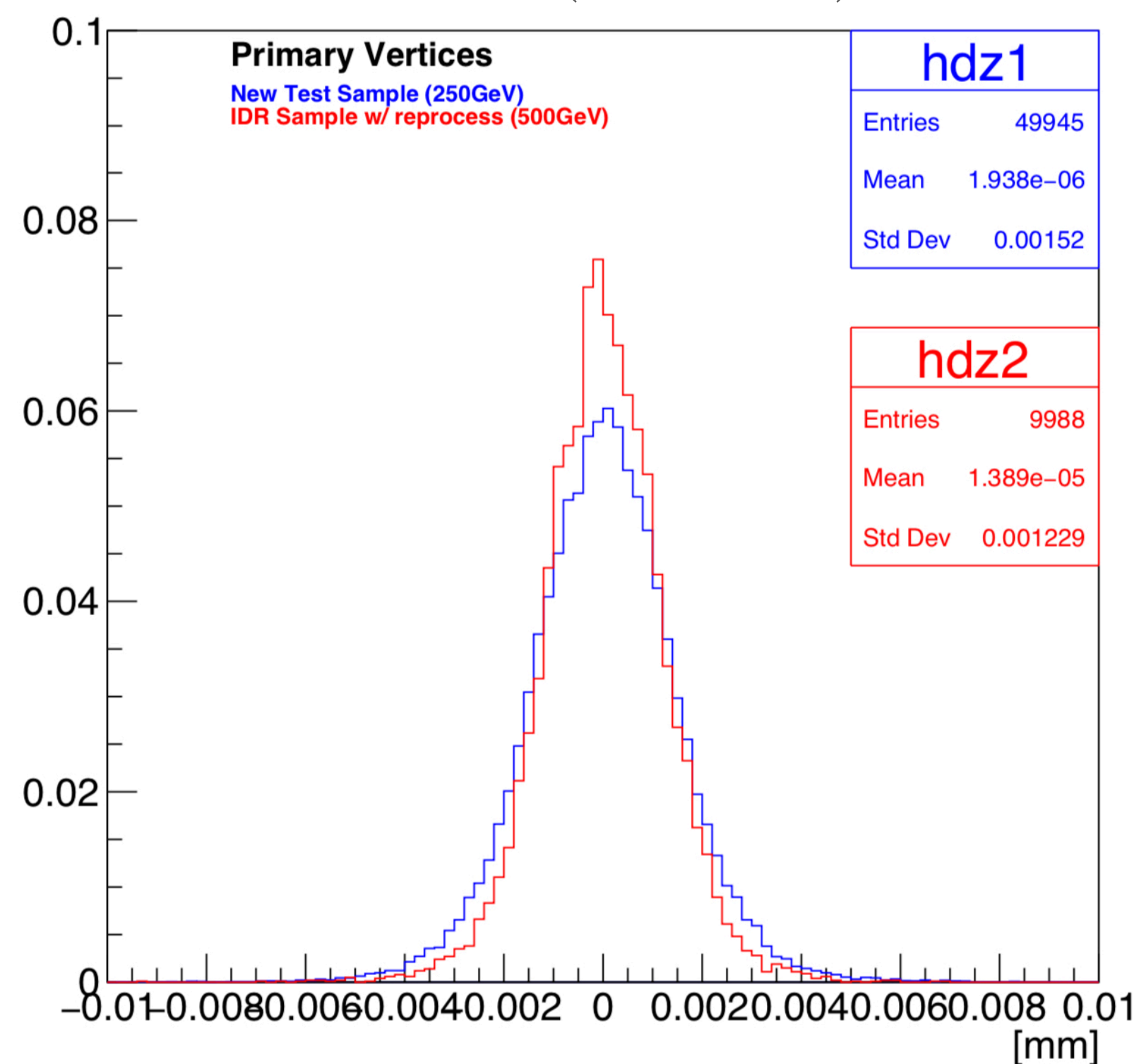
S

Primary Vertex : z-position residual

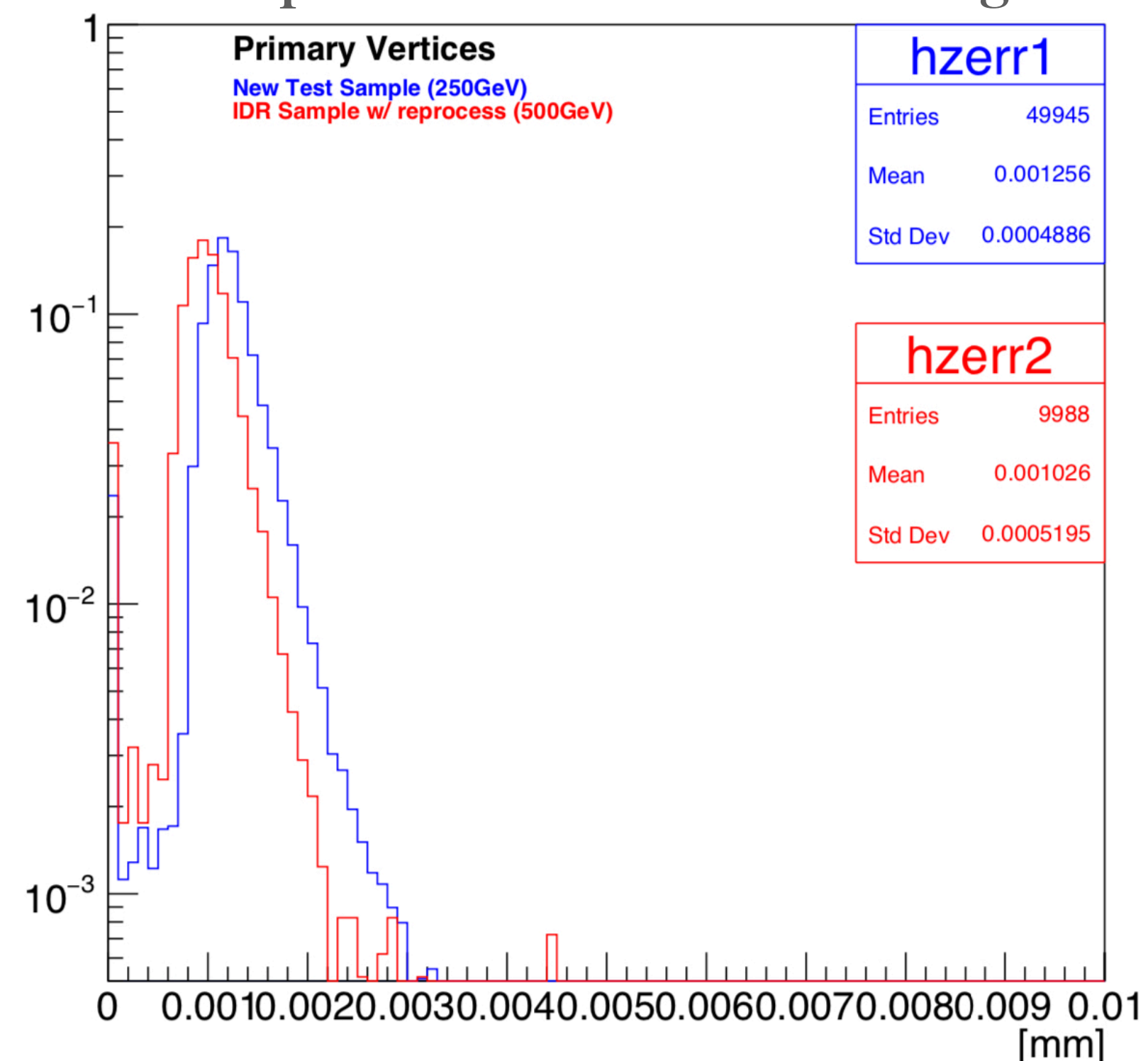
Blue : New test sample

Red : IDR sample w/ reprocess (500 GeV, w/ IP smearing)

residual (Rec - MC)



z position error from fitting

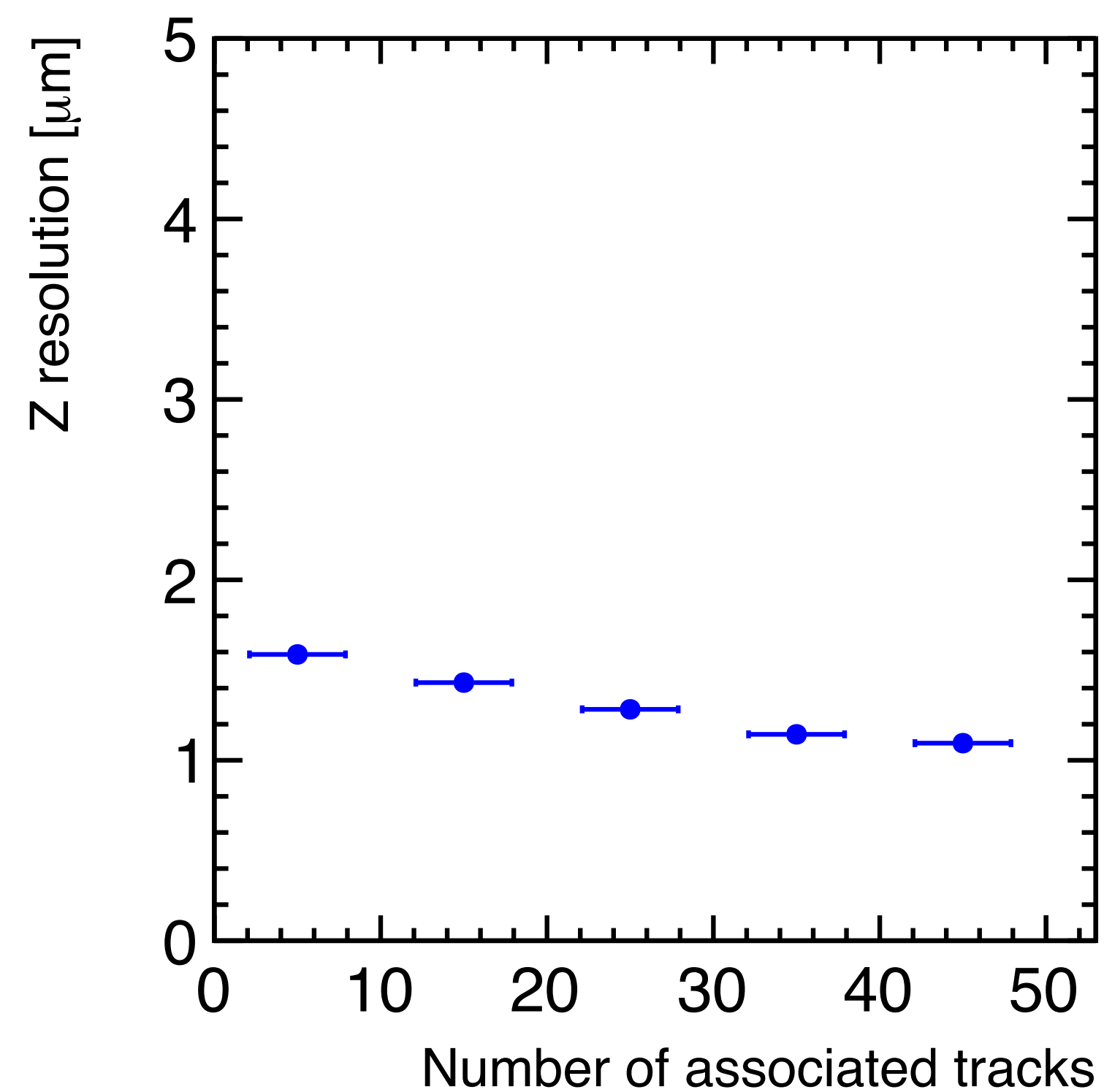


New test sample is slightly worse in z-position resolution, probably reflecting track parameter errors.

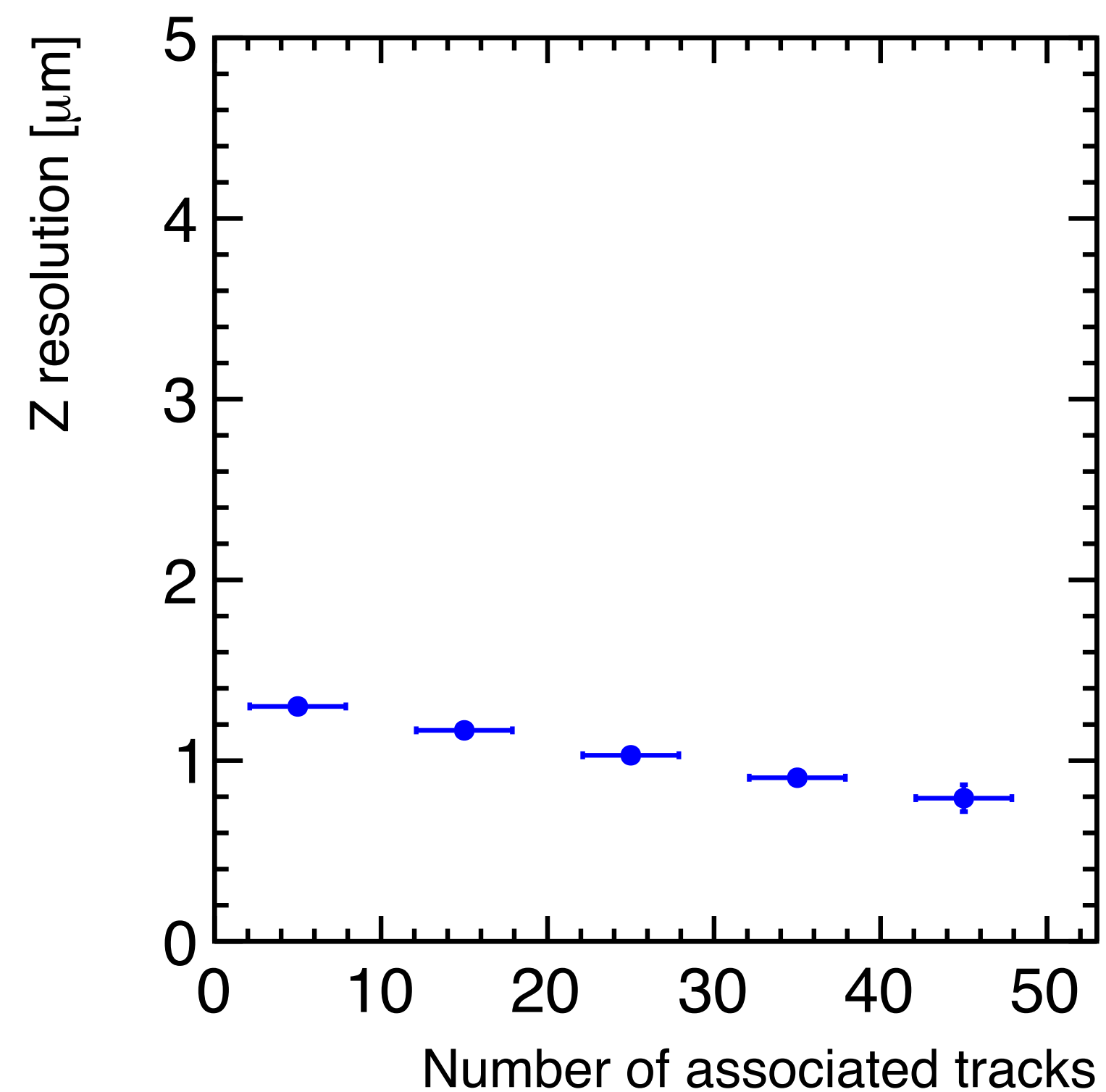
No clear sign of problems

Primary Vertex : z-position resolution vs # of tracks in vtx

New test sample



IDR sample w/ reprocess

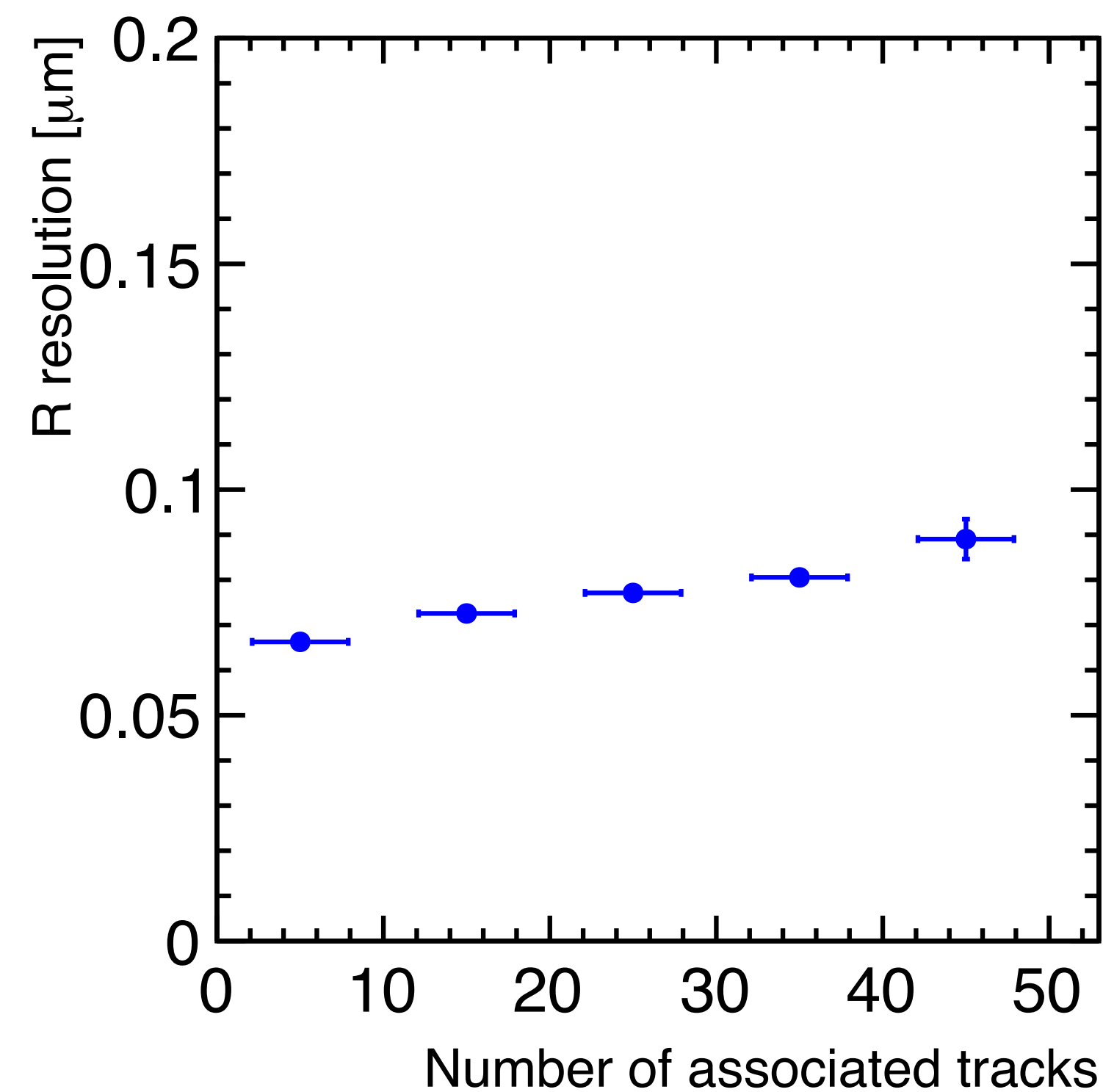


No clear sign of problems

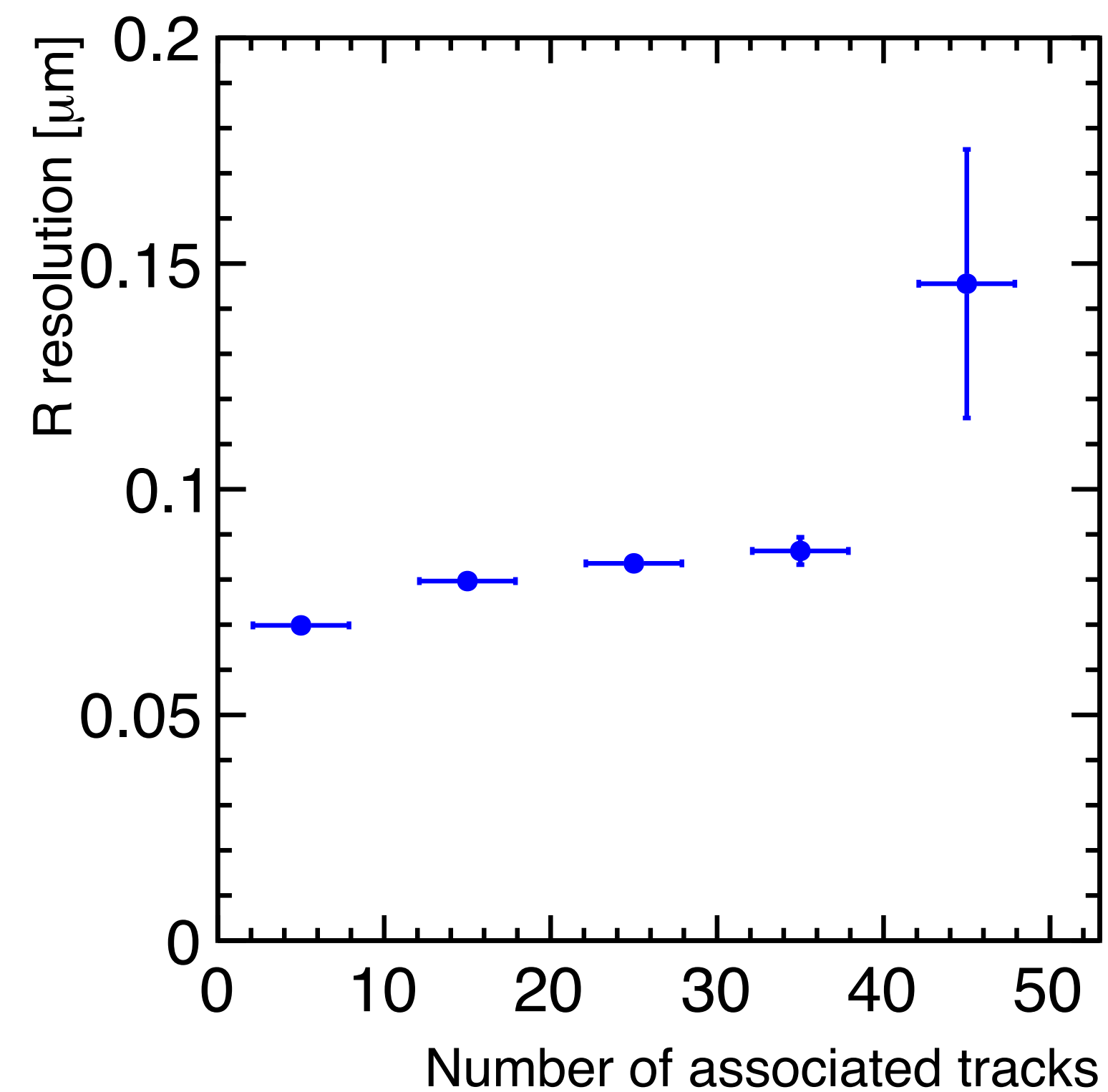
Primary Vertex : r-position resolution vs # of tracks in vtx

$$r := \sqrt{x^2 + y^2}$$

New test sample



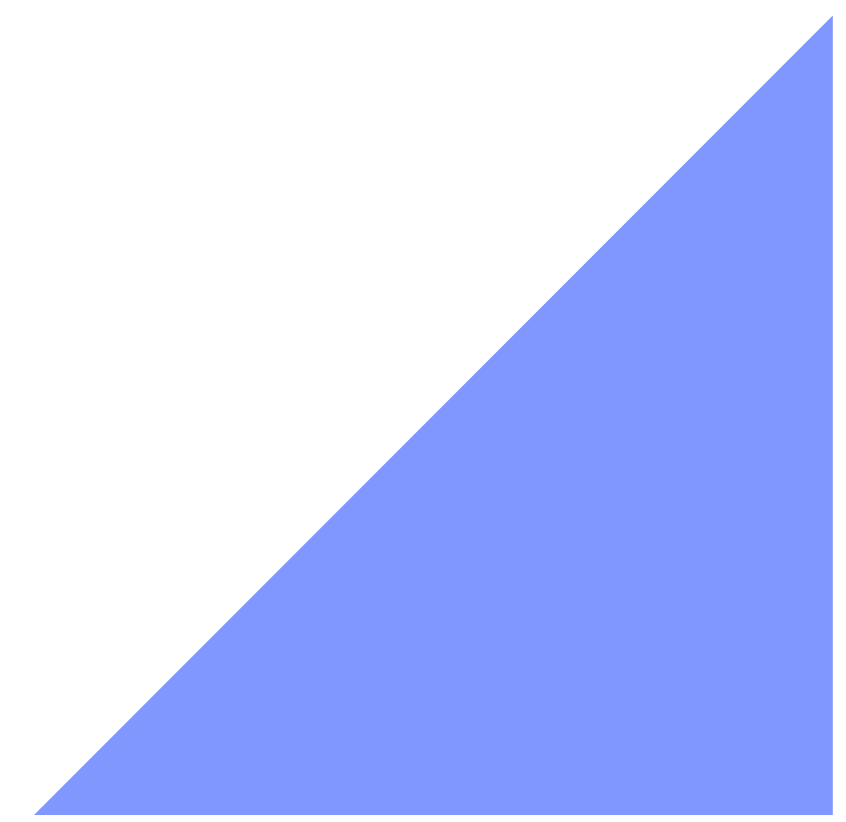
IDR sample w/ reprocess



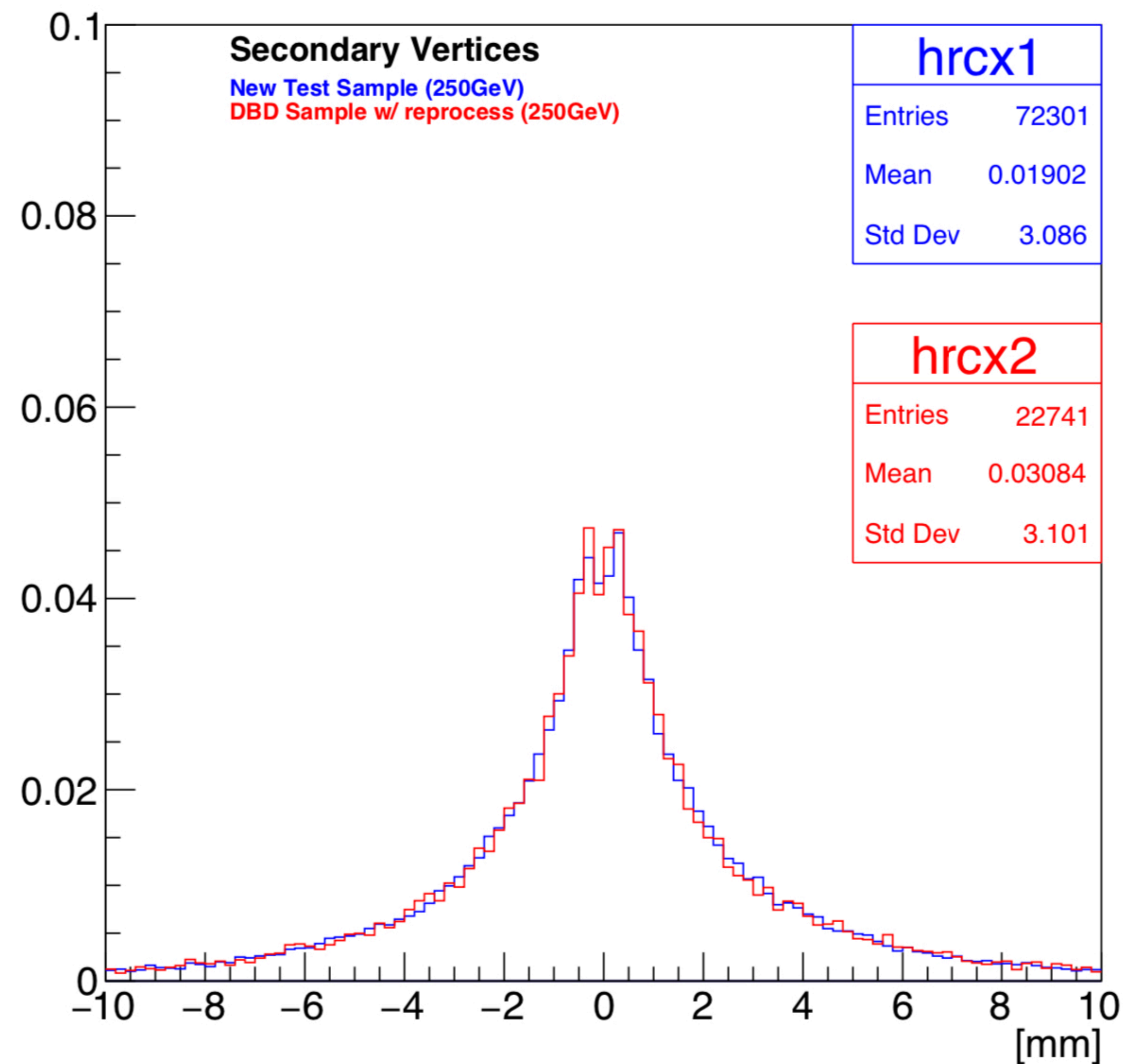
No clear sign of problems

Secondary Vertex

Comparison between New test sample and “DBD” sample (250 GeV, w/o IP smearing)



Secondary Vertex : x-position



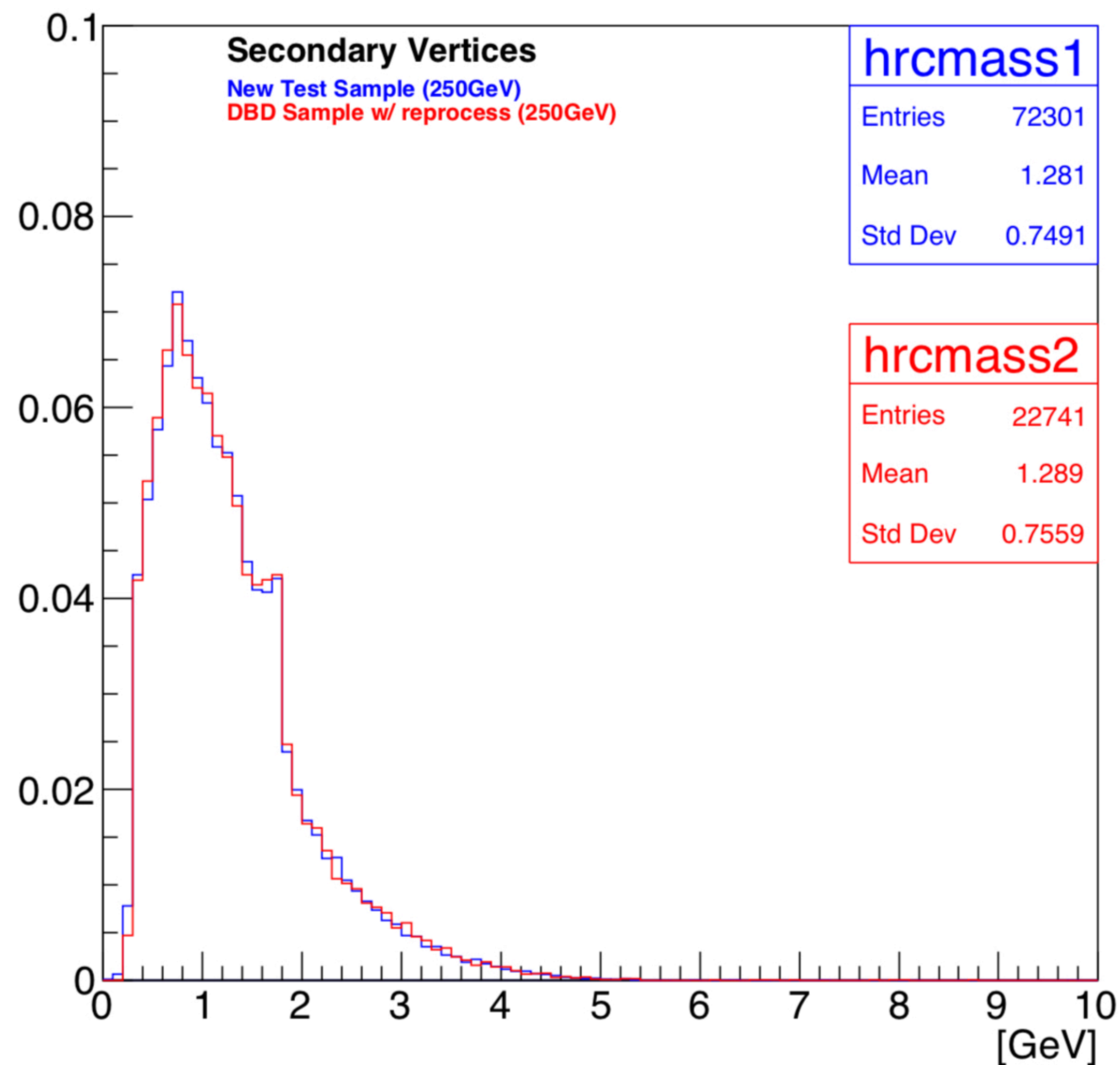
Blue : New test sample

Red : DBD sample w/ reprocess (250 GeV, w/
o IP smearing)

See backup for y and z.

No clear difference

Secondary Vertex : Invariant mass of charged tracks

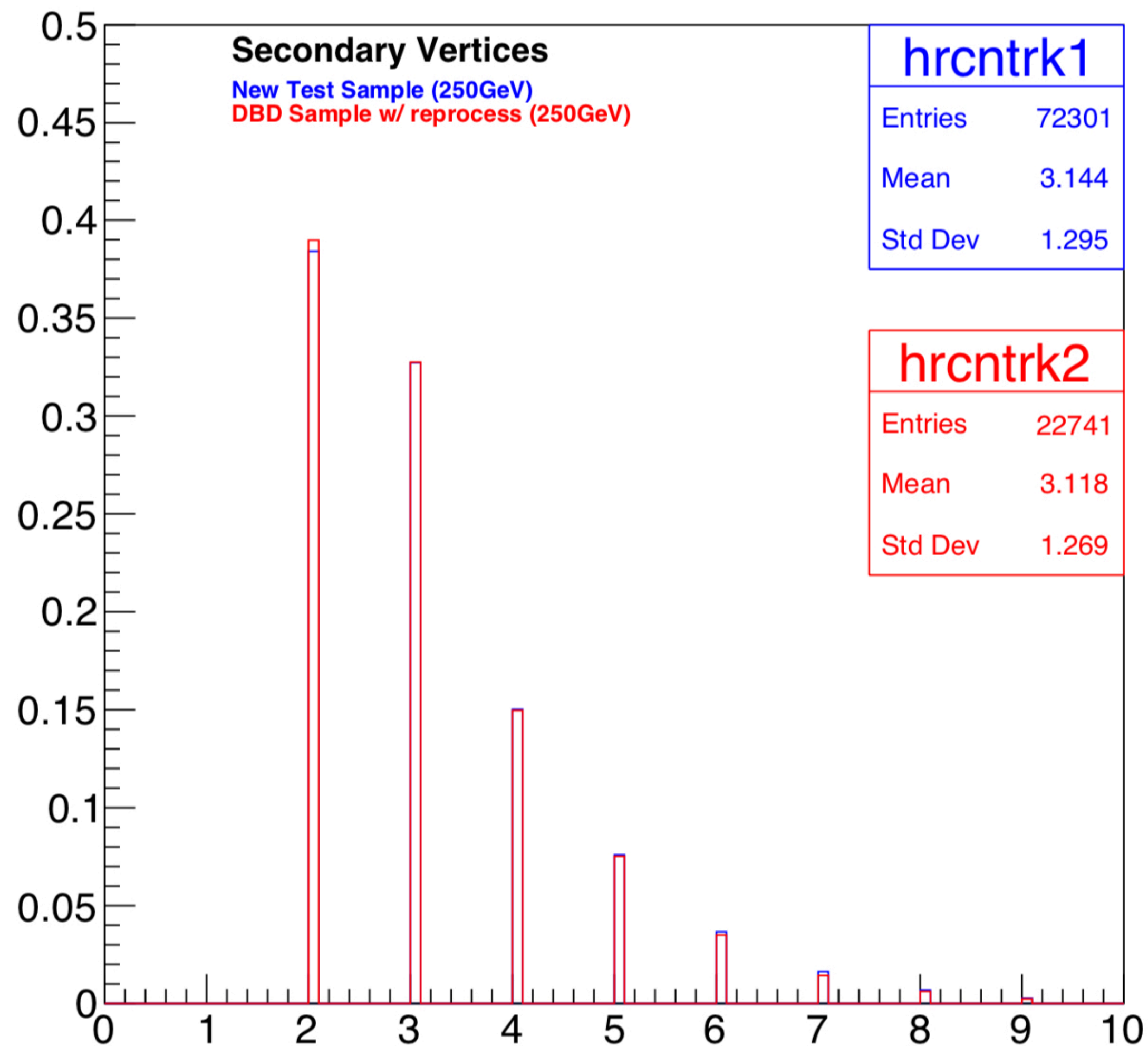


Blue : New test sample

Red : DBD sample w/ reprocess (250 GeV, w/
o IP smearing)

No clear difference

Secondary Vertex : # of tracks

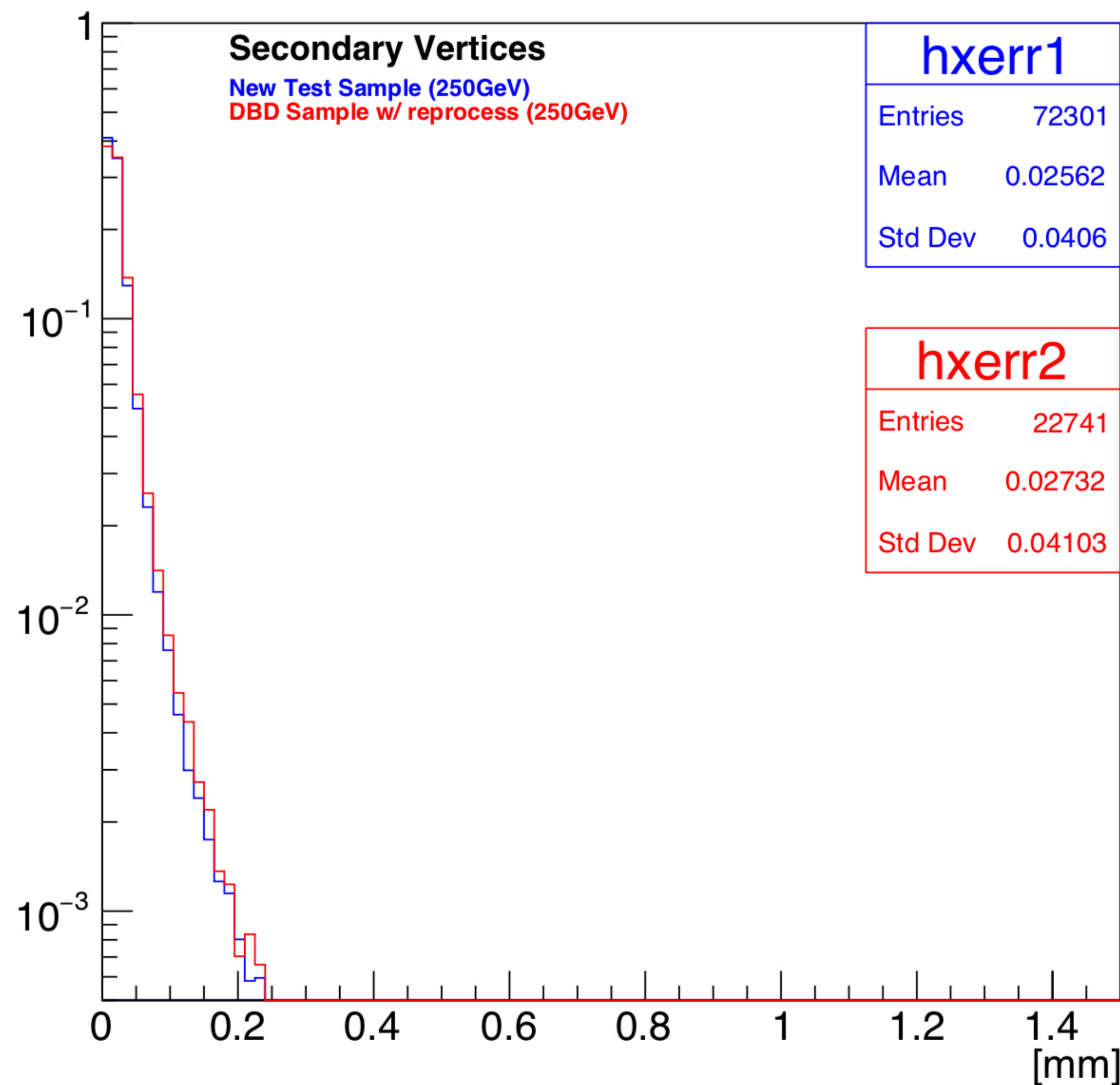


Blue : New test sample

Red : DBD sample w/ reprocess (250 GeV, w/
o IP smearing)

No clear difference

Secondary Vertex : x-position error form vtx fitting



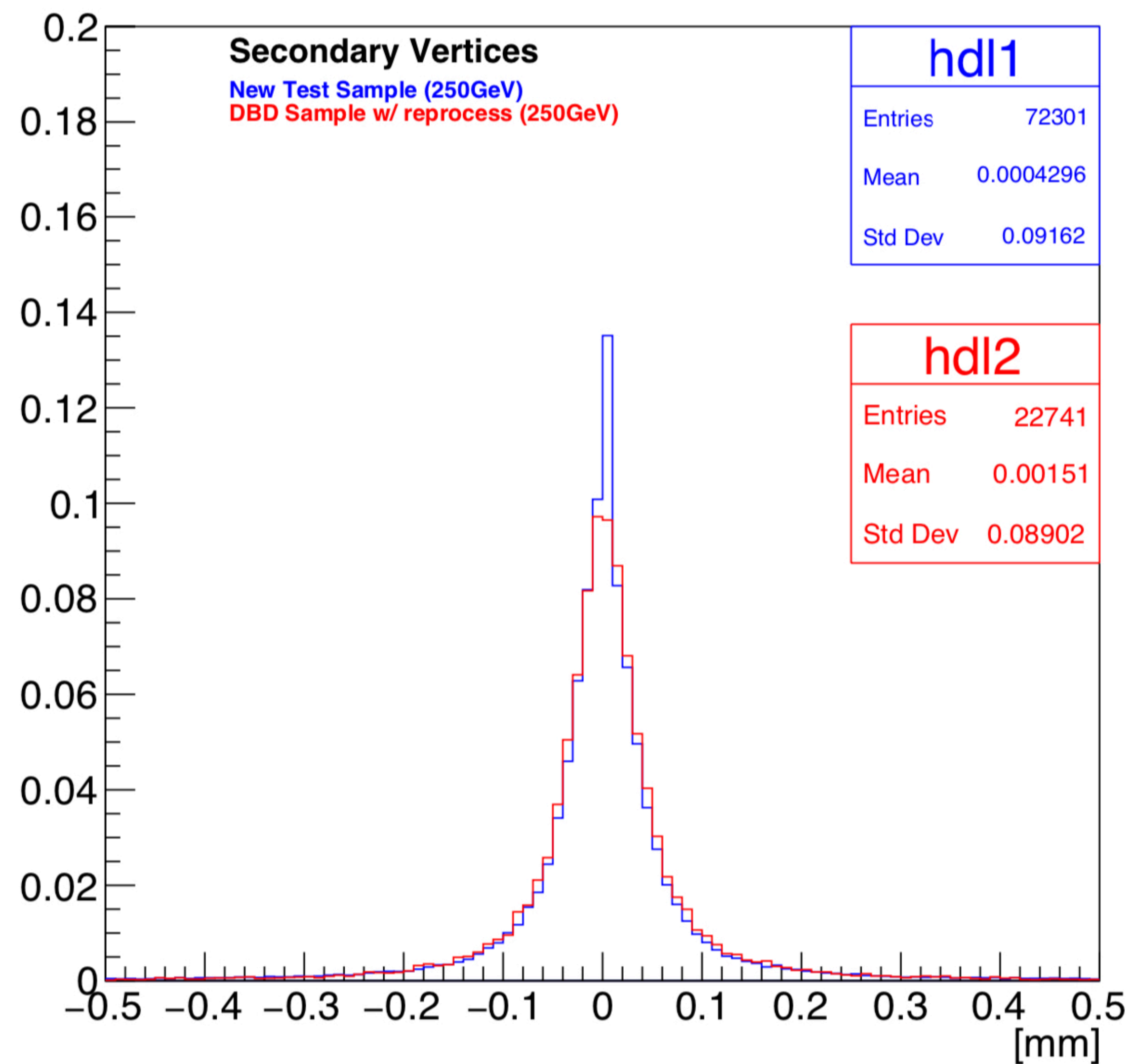
Blue : New test sample

Red : DBD sample w/ reprocess (250 GeV, w/
o IP smearing)

See backup for y and z.

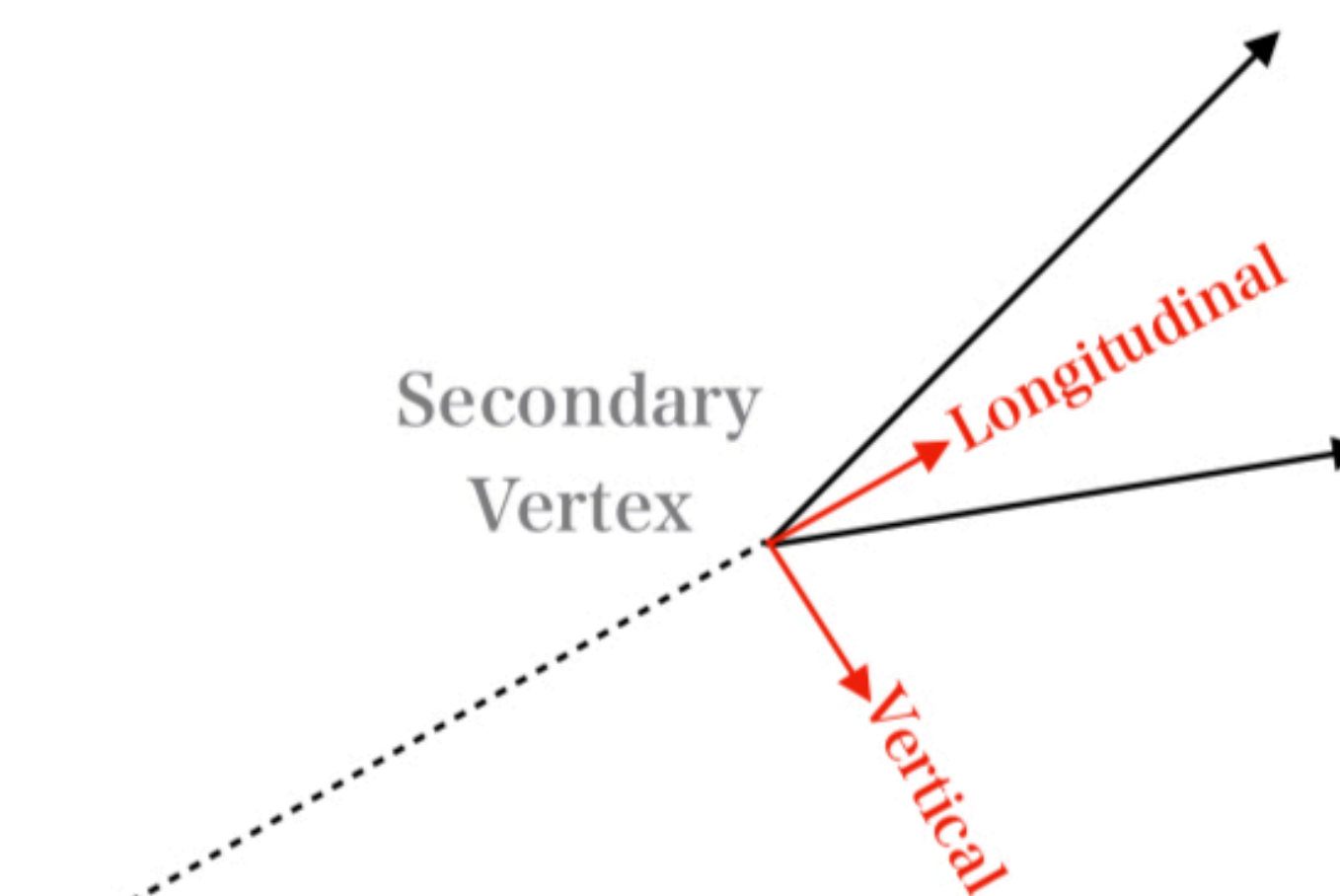
No clear difference

Secondary Vertex : Longitudinal resolution



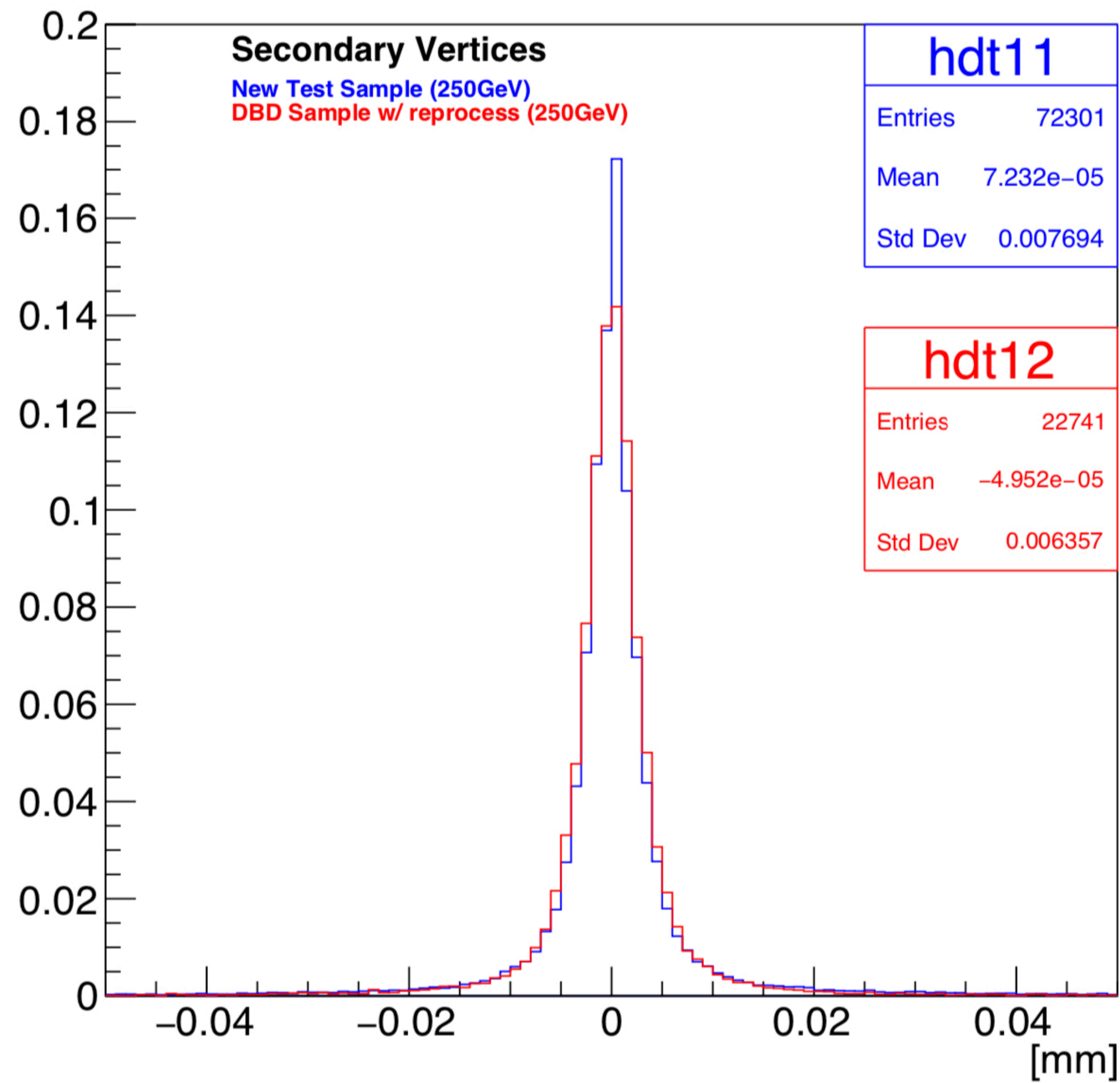
Blue : New test sample

Red : DBD sample w/ reprocess (250 GeV, w/
o IP smearing)

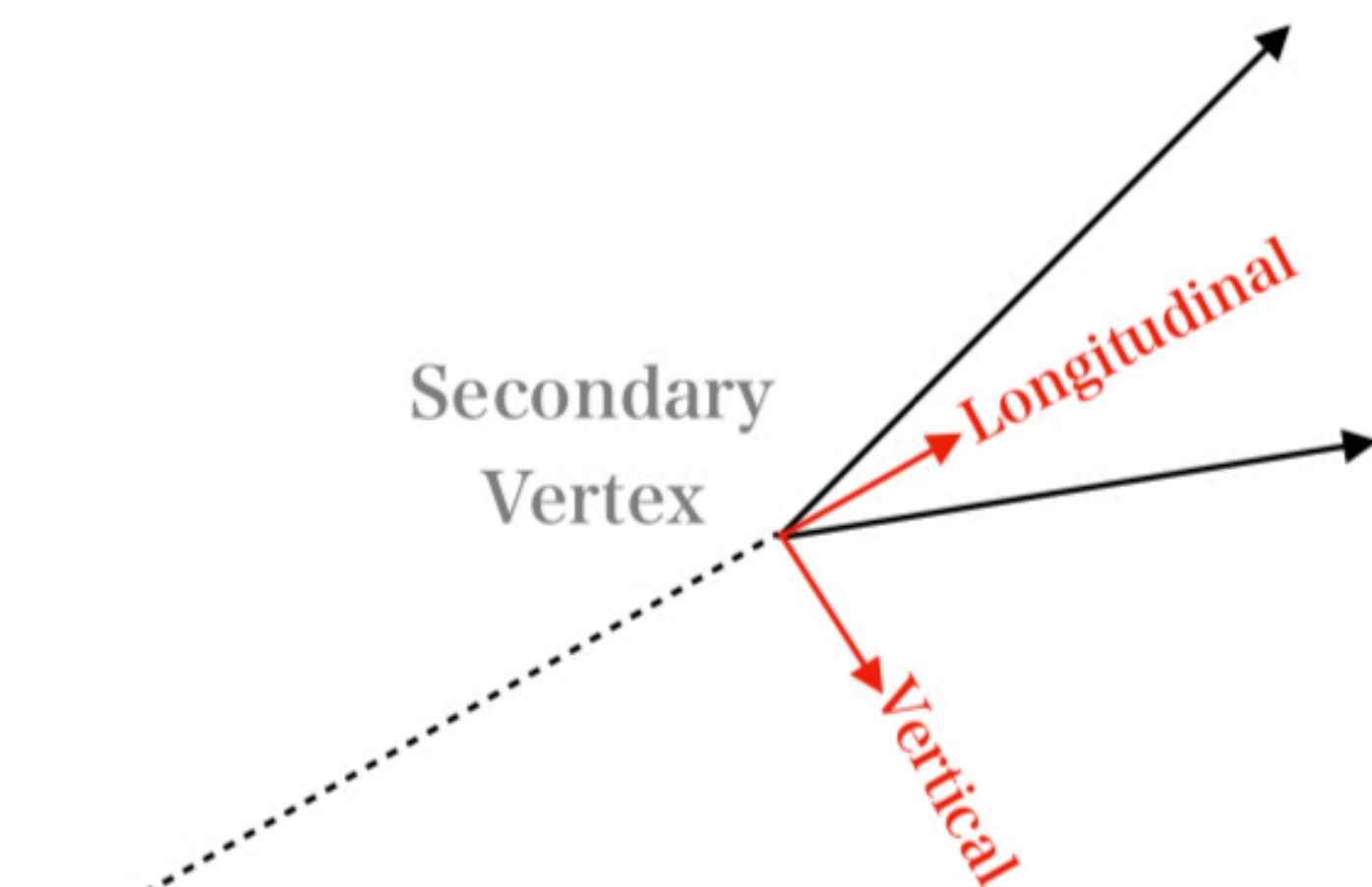


Looks slightly improved

Secondary Vertex : Transverse resolution



Blue : New test sample
Red : DBD sample w/ reprocess (250 GeV, w/ o IP smearing)



Looks slightly improved

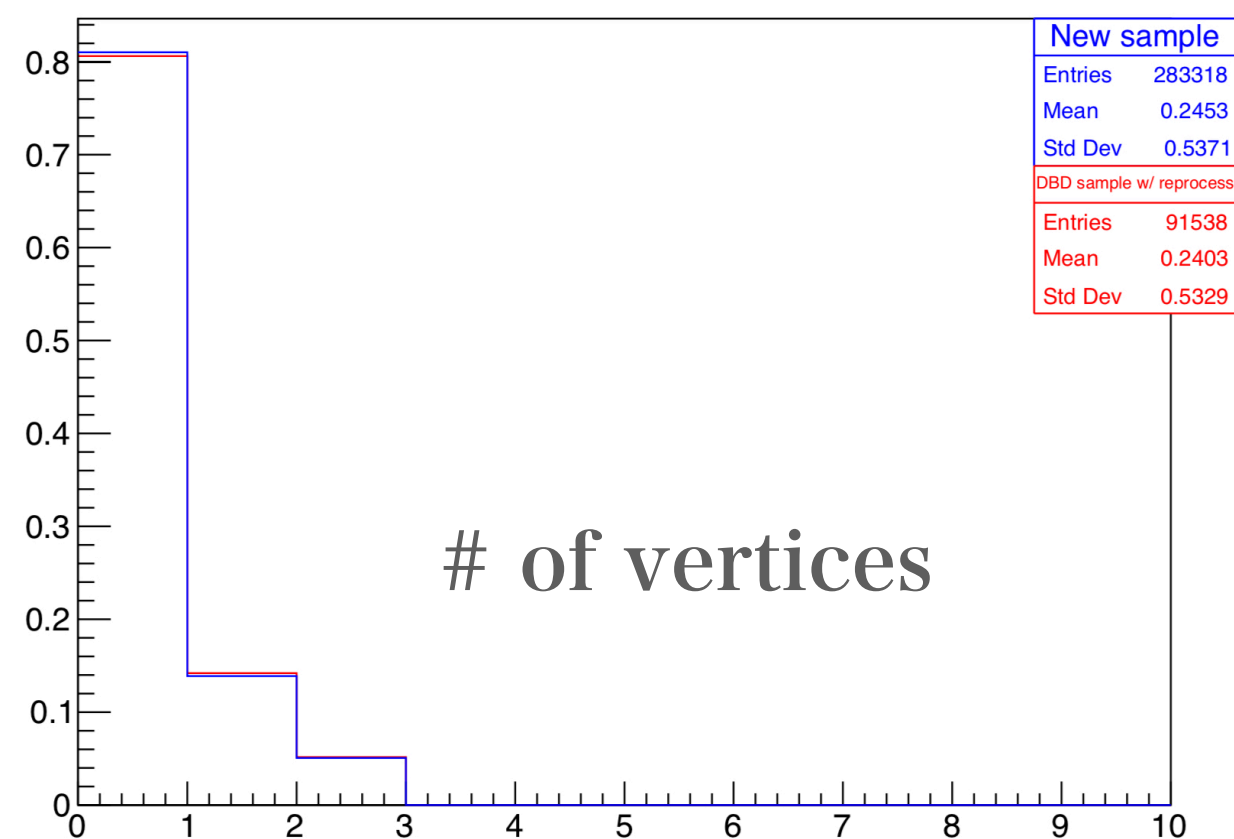
Input variables for flavour tagging

Comparison between New test sample and “DBD” sample (250 GeV, w/o IP smearing)

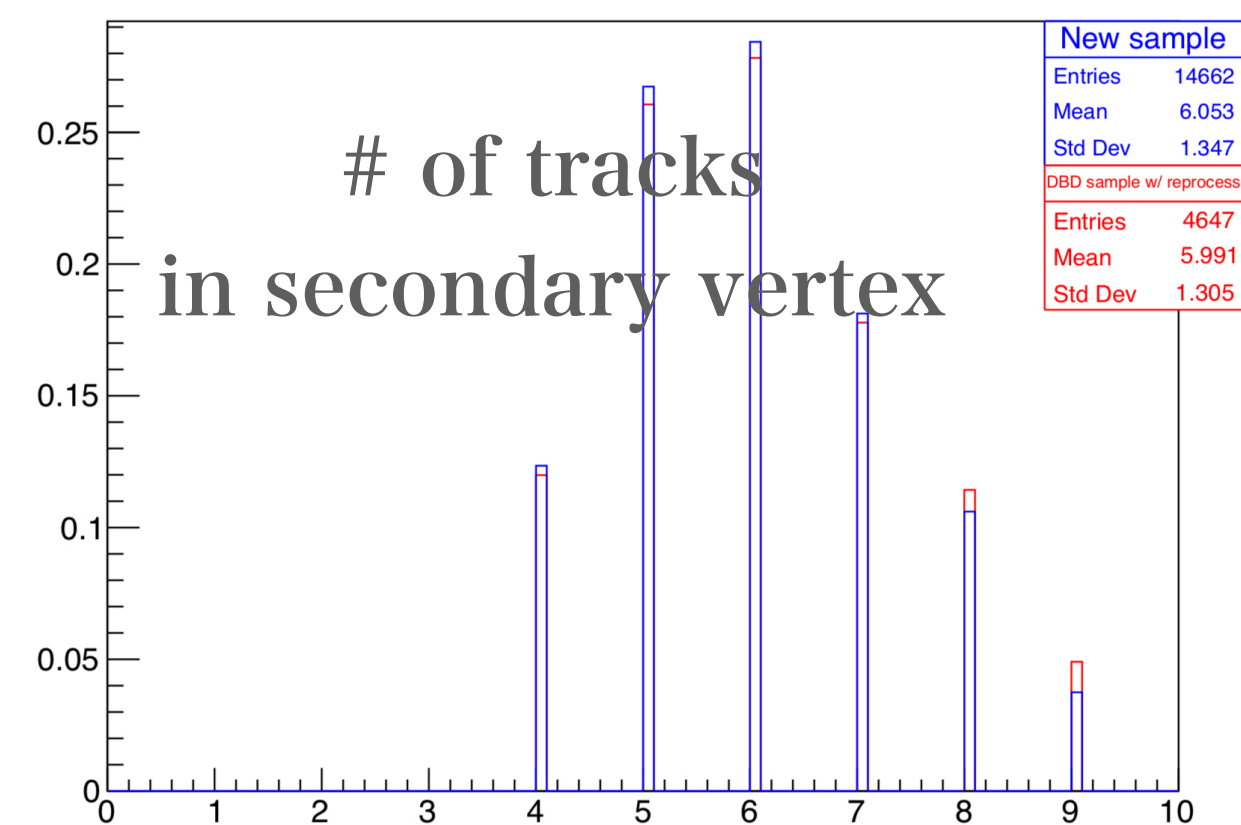


Examples of input variables for flavor tagging

nvtx, trk1d0sig!=0



vtxmult, nvtx>=2

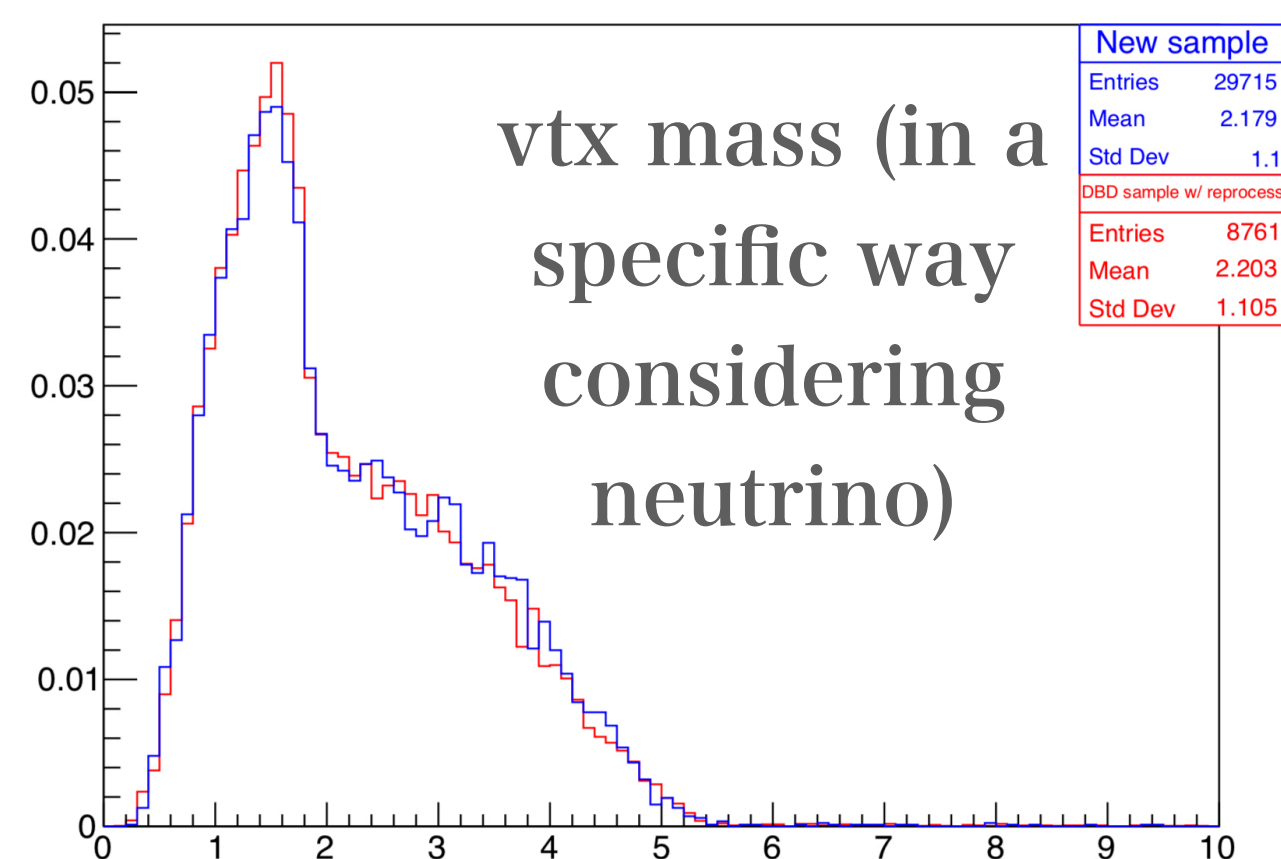


Blue : New test sample

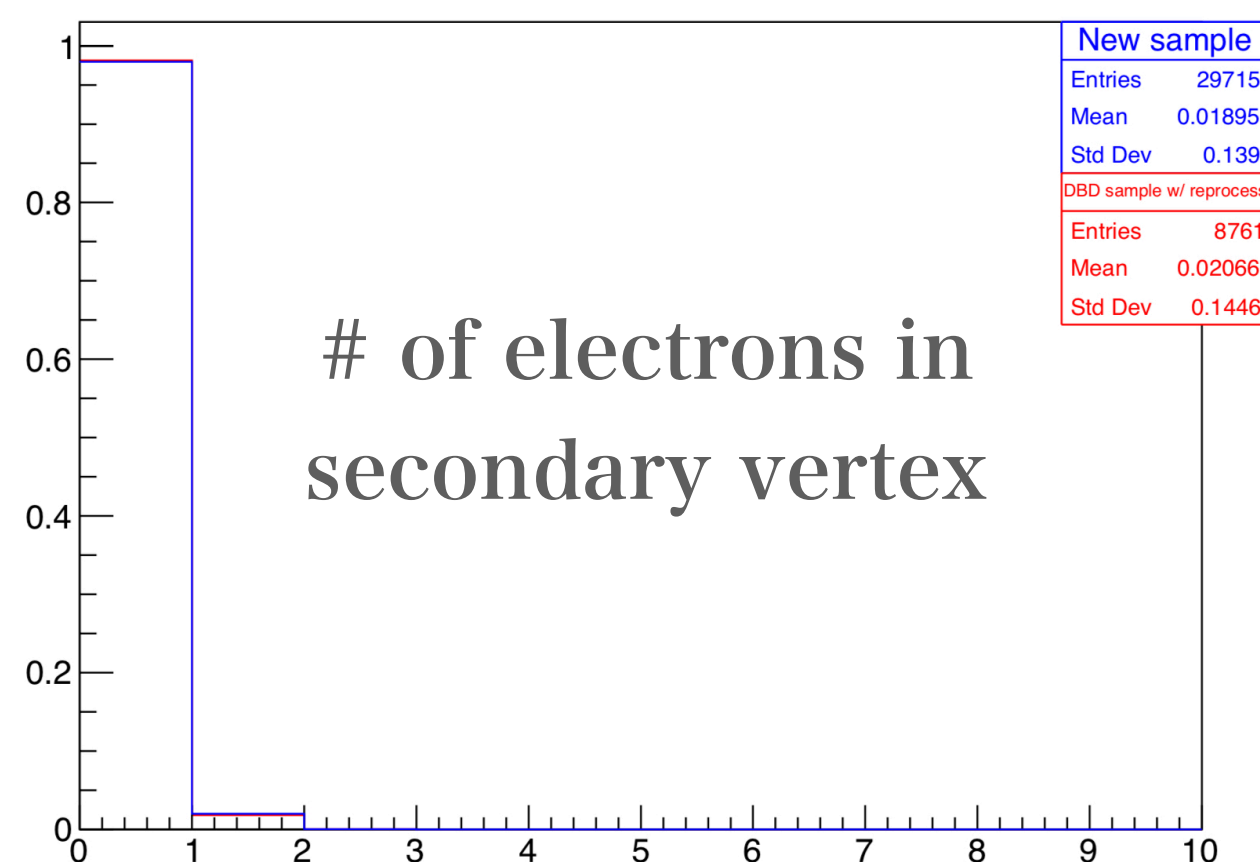
Red : DBD sample w/ reprocess (250 GeV, w/ o IP smearing)

The other plots are also checked but no clear difference found.

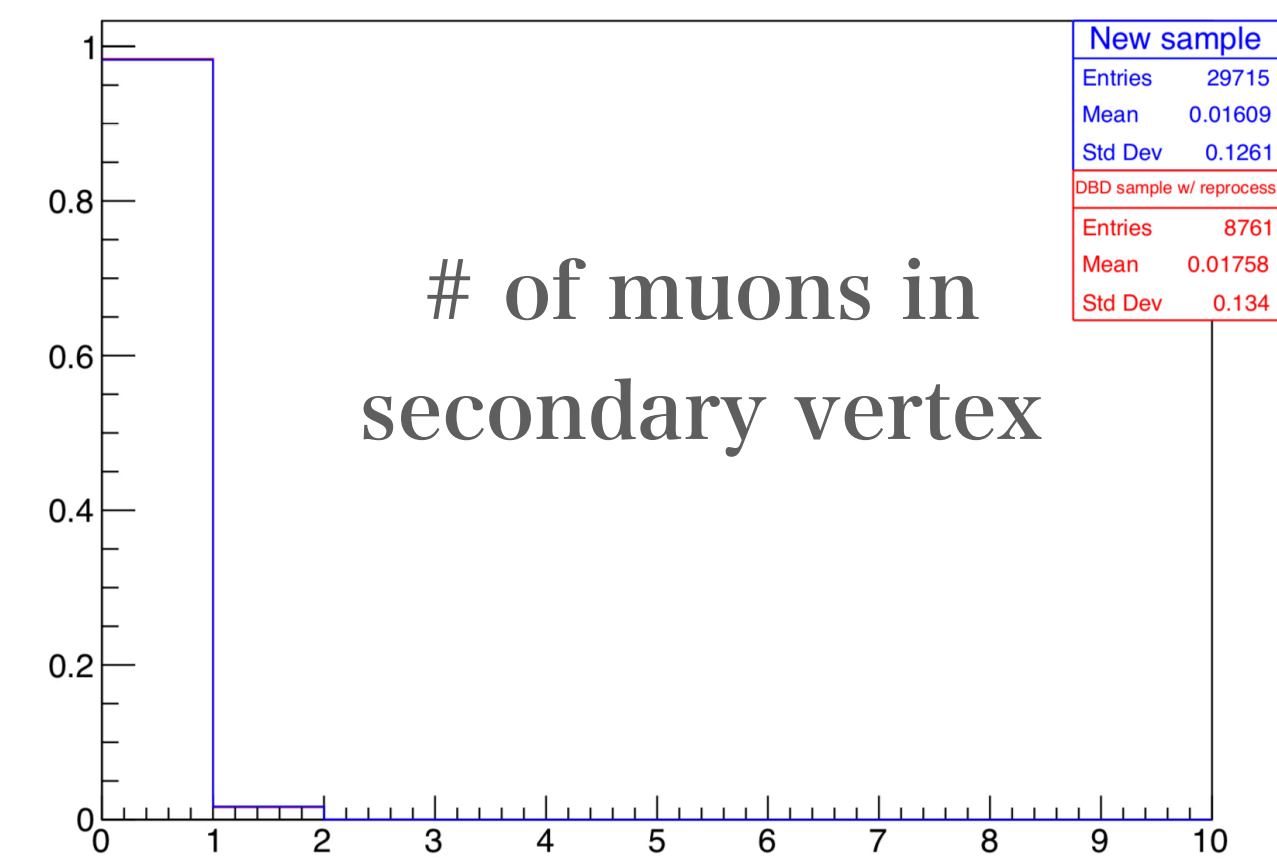
vtxmasspc , nvtx==1&&nvtxall==1&&trk1d0sig!=0



nelectron , nvtx==1&&nvtxall==1&&trk1d0sig!=0



nmuon, nvtx==1&&nvtxall==1&&trk1d0sig!=0



No clear difference

Summary

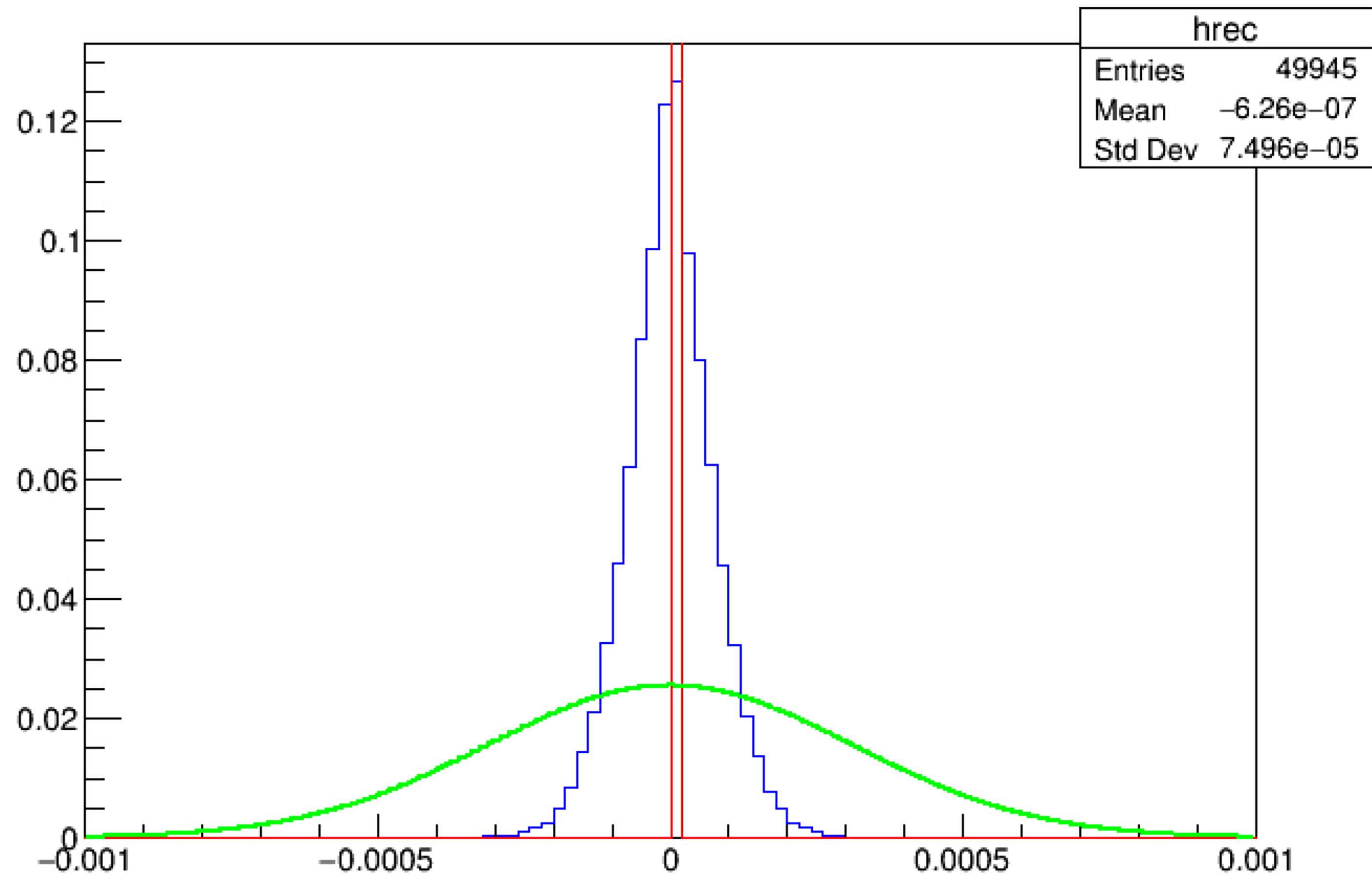
New test sample (e2e2h) is checked comparing with previous MC samples (DBD, IDR)

No clear sign of problems found (slight improvement can be seen in some cases)

Dedicated test samples for flavour tagging (b,c,q) allows us to check further (flavour tag performance etc)

Backup

Primary Vertex : x-position



New test sample,

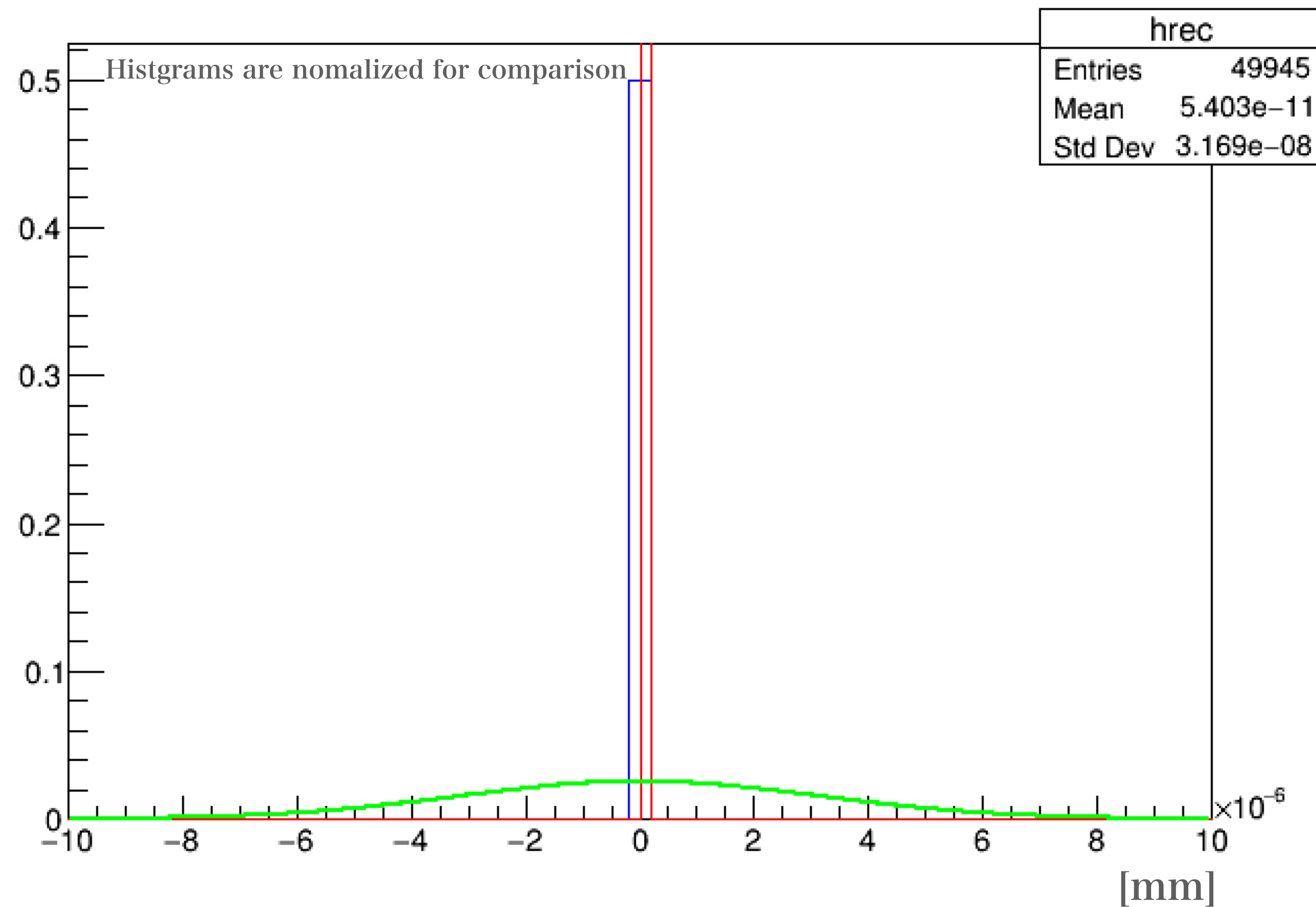
Blue : Reconstructed

Red : MC = 0

Green : Gaussian with sigma of beam spot constraint (313.e-6)

How we constrain vertex position?
A virtual point having central value of 0 and sigma of 313.e-6 is used in vertex fitting.

Primary Vertex : y-position



New test sample,

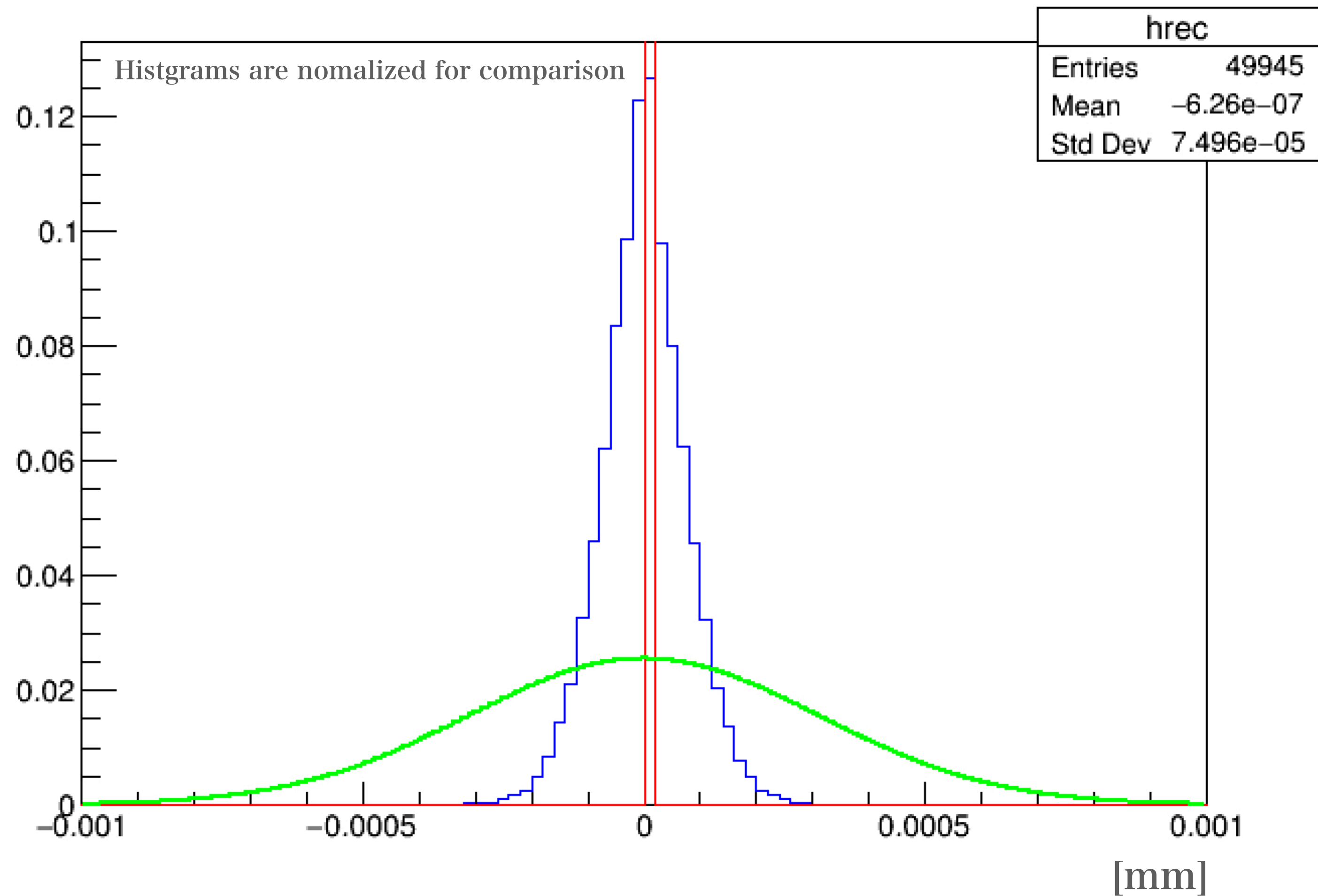
Blue : Reconstructed

Red : MC = 0

Green : Gaussian with sigma of beam spot
constraint ($3.14e-6$)

Reconstructed position is almost 0 due to the
strongest constraint.

Primary Vertex : x-position



New test sample,

Blue : Reconstructed

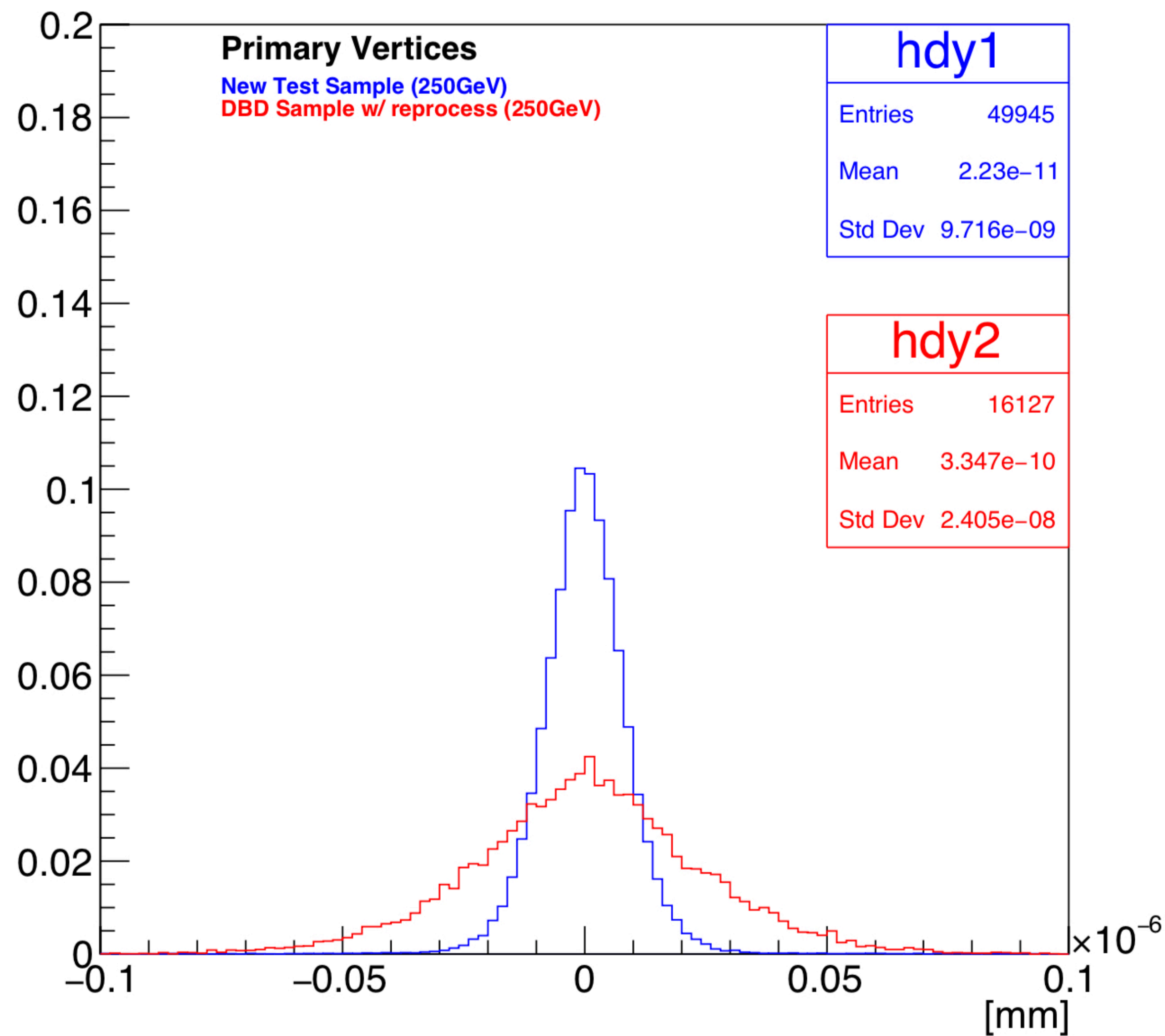
Red : MC = 0

Green : Gaussian with sigma of beam spot constraint (313.e-6)

Reconstructed position is intermediate in width between z and y.

Primary Vertex : y-position residual

= (Rec - MC)

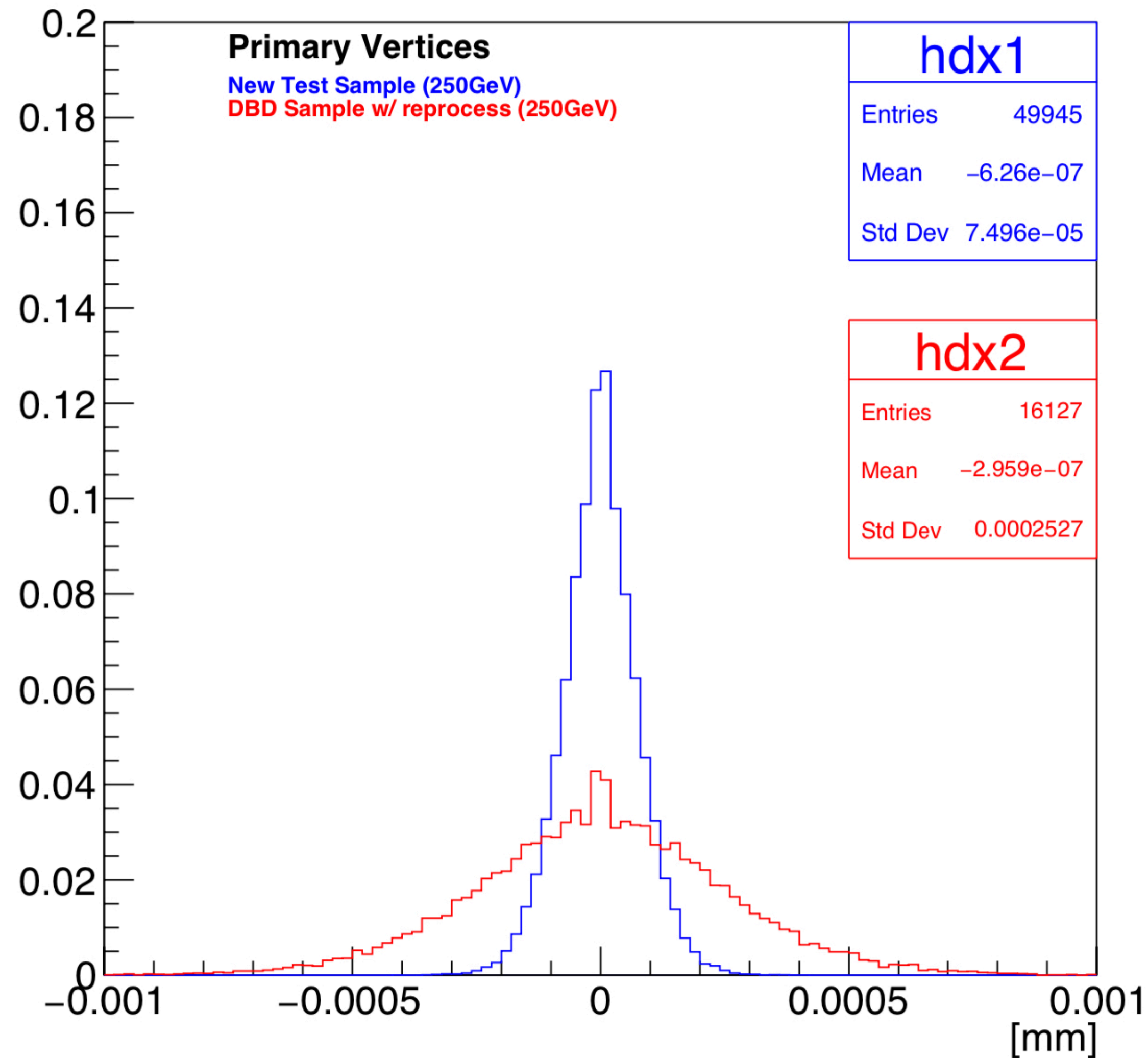


Blue : New test sample

Red : DBD sample w/ reprocess (250 GeV, w/
o IP smearing)

Primary Vertex : x-position residual

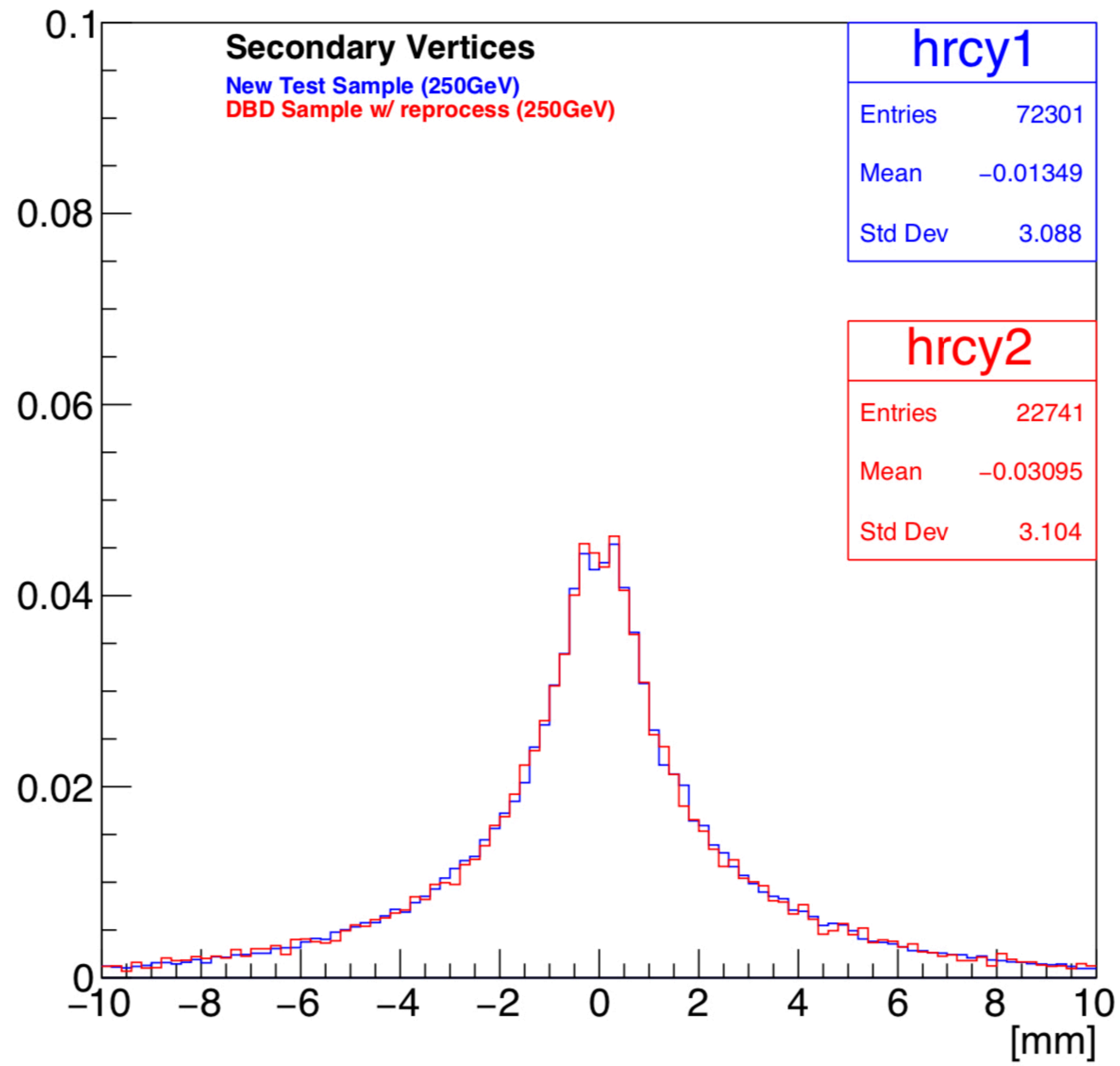
= (Rec - MC)



Blue : New test sample

Red : DBD sample w/ reprocess (250 GeV, w/
o IP smearing)

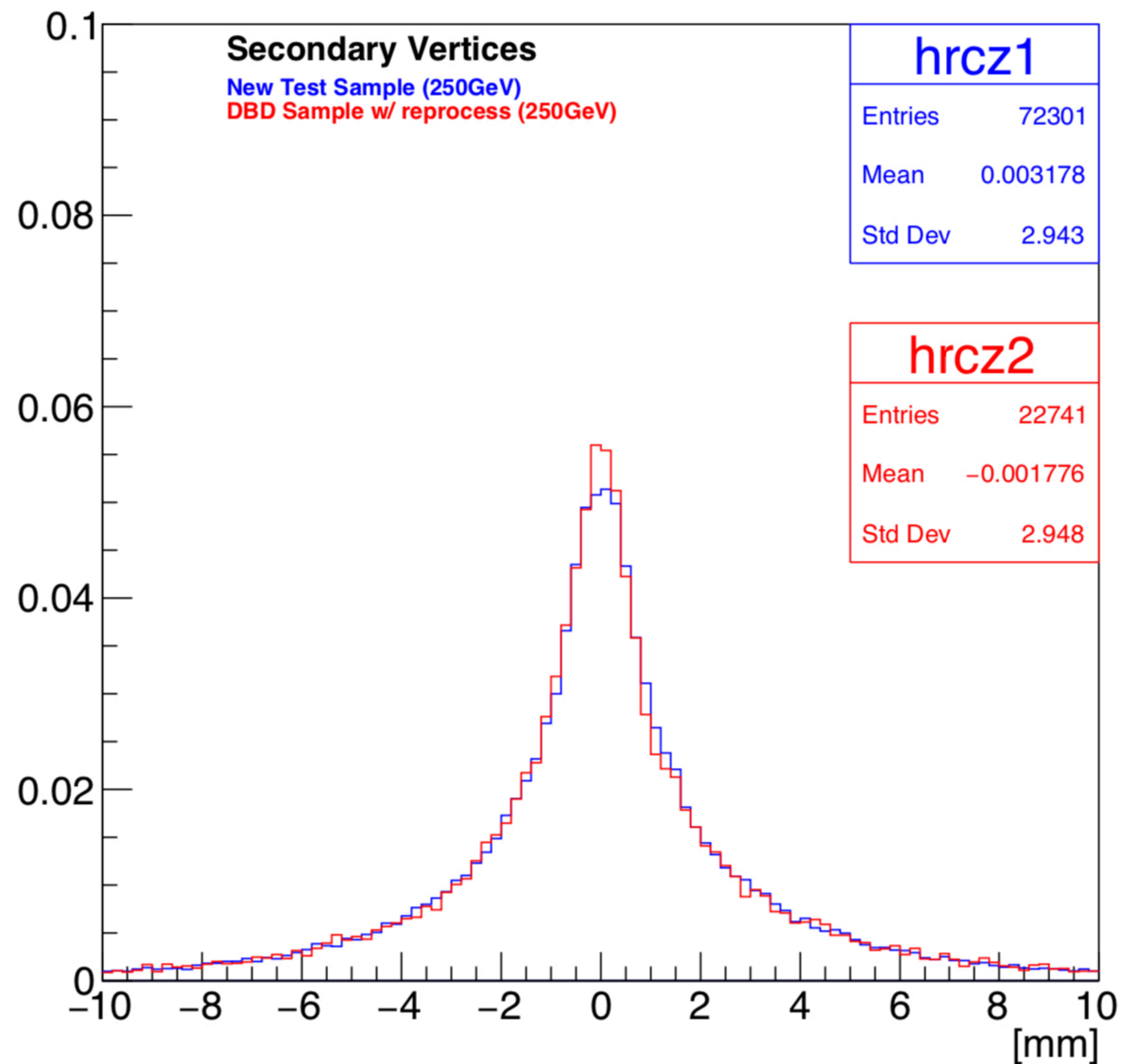
Secondary Vertex : y-position



Blue : New test sample

Red : DBD sample w/ reprocess (250 GeV, w/
o IP smearing)

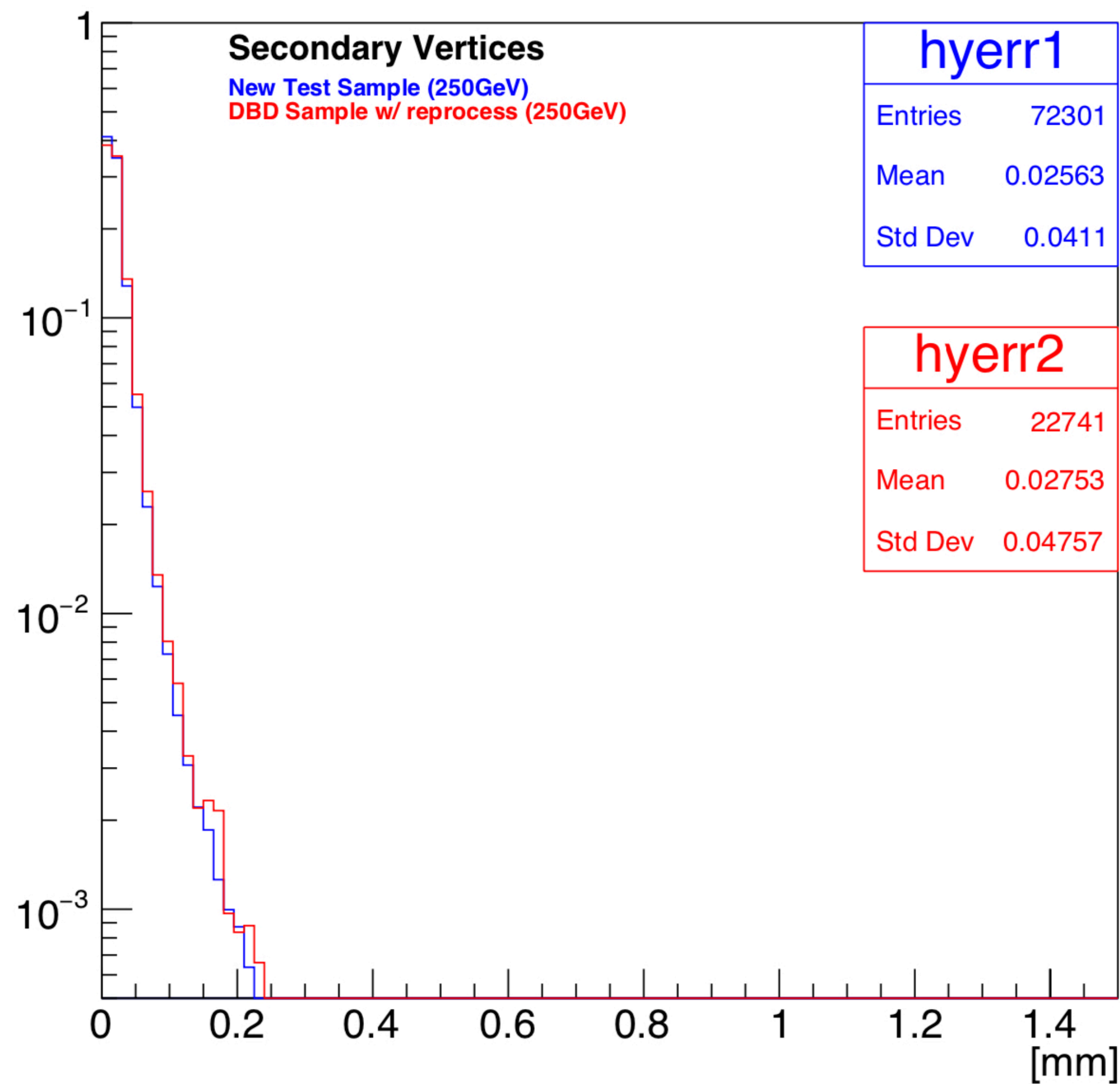
Secondary Vertex : z-position



Blue : New test sample

Red : DBD sample w/ reprocess (250 GeV, w/
o IP smearing)

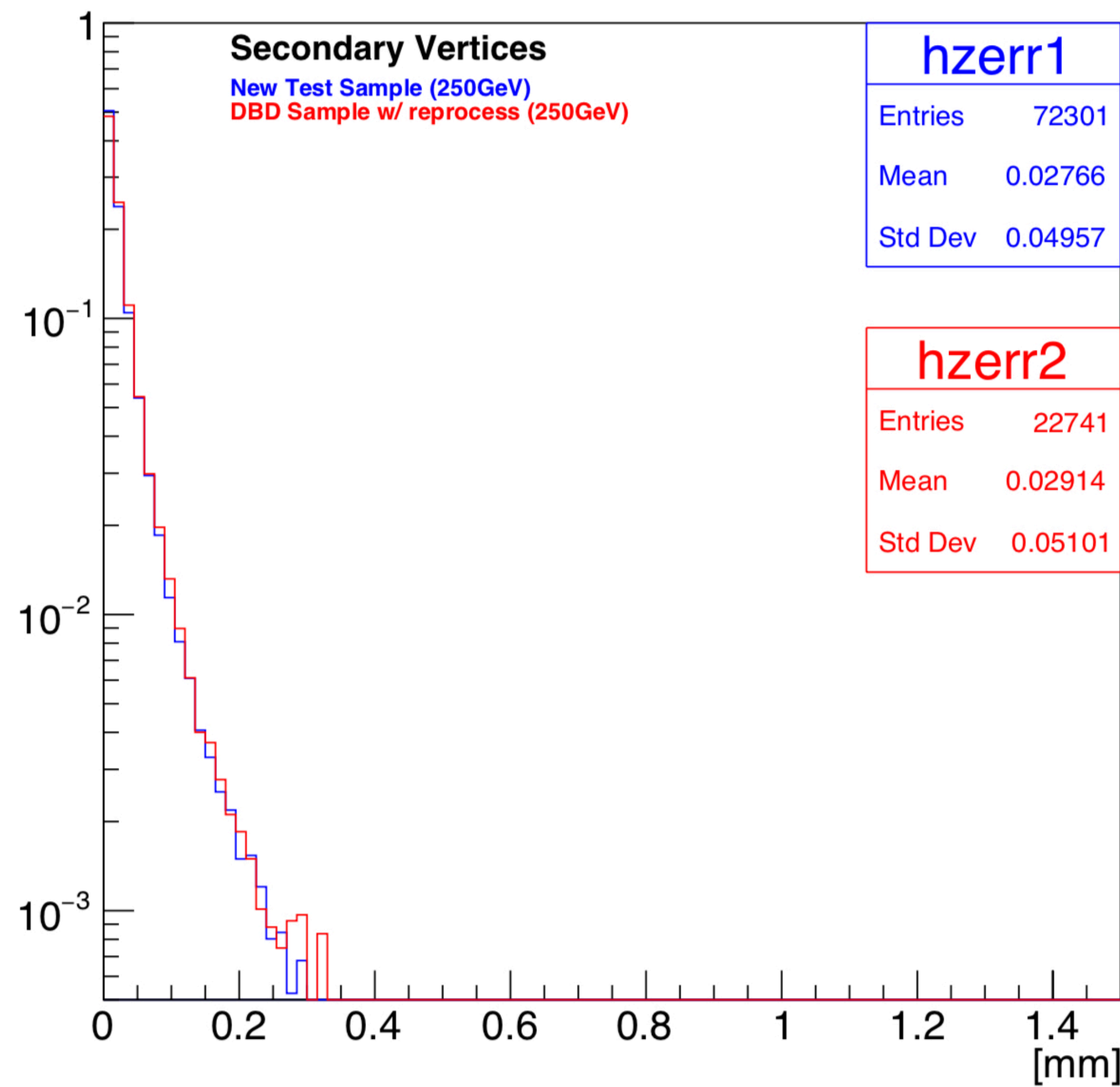
Secondary Vertex : y-position error from vtx fitting



Blue : New test sample

Red : DBD sample w/ reprocess (250 GeV, w/
o IP smearing)

Secondary Vertex : z-position error from vtx fitting

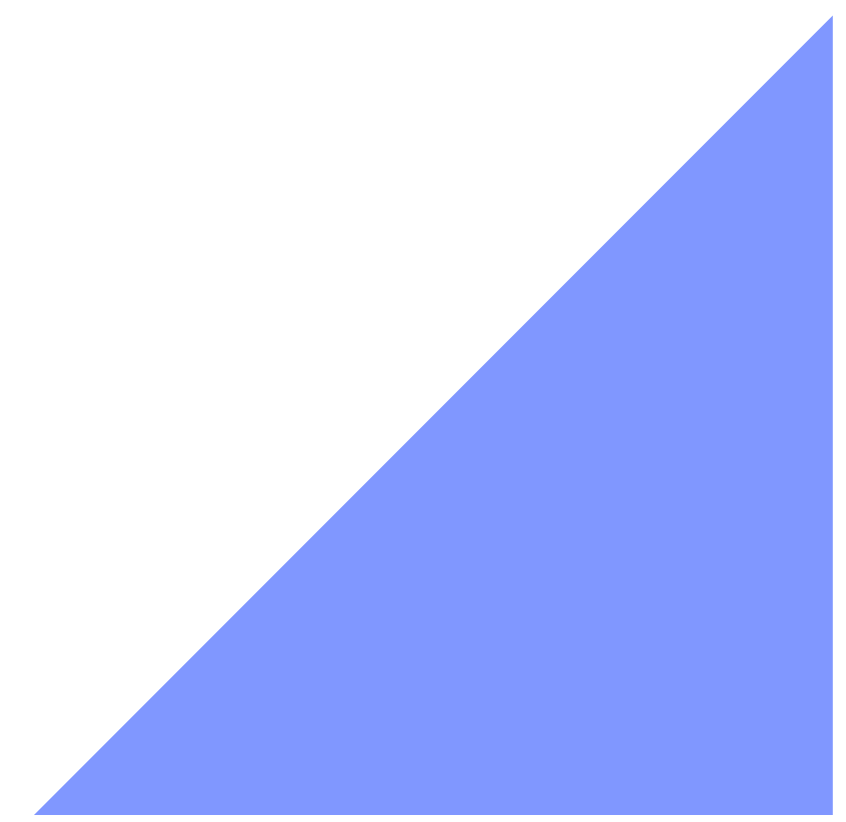


Blue : New test sample

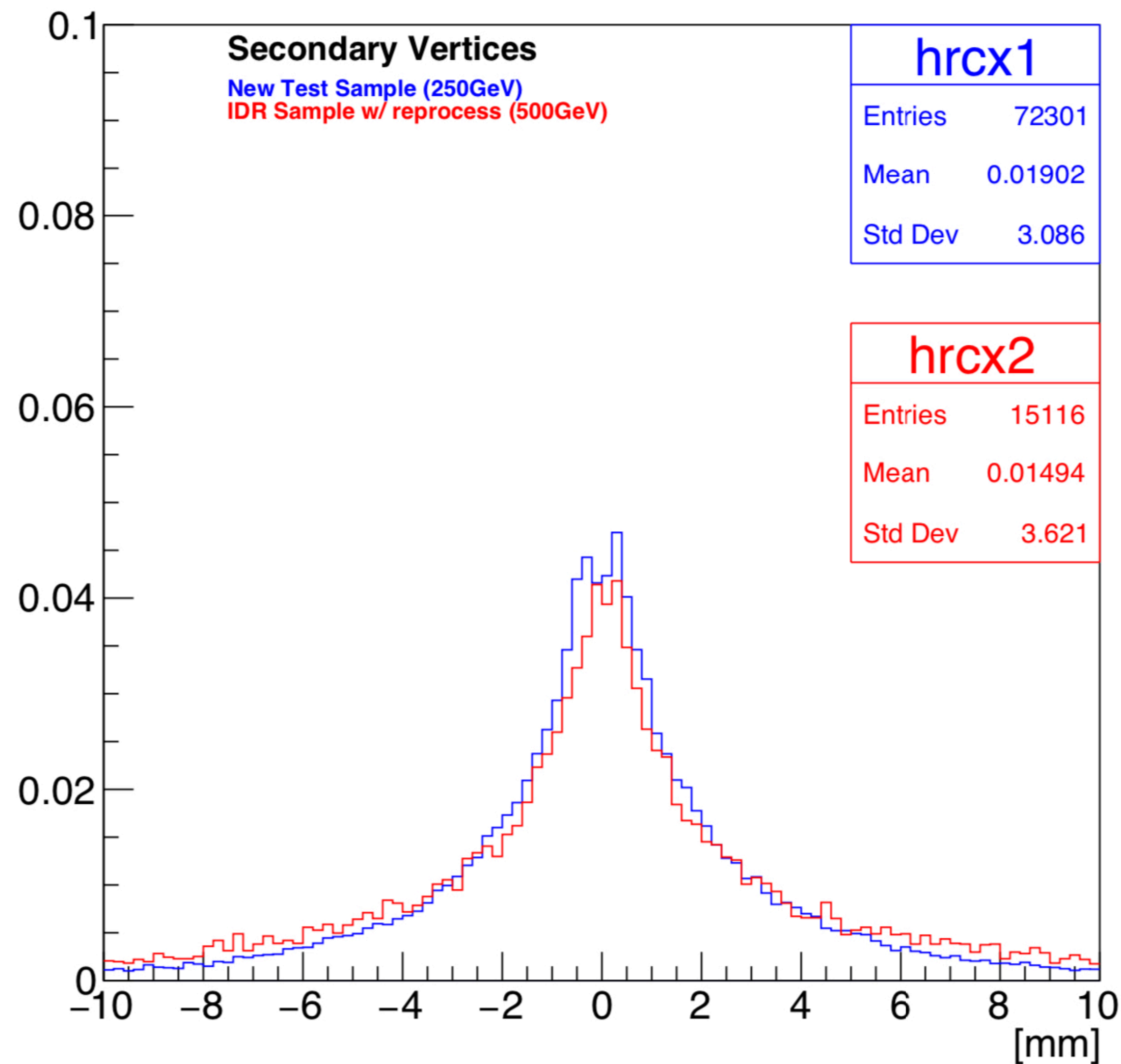
Red : DBD sample w/ reprocess (250 GeV, w/
o IP smearing)

Secondary Vertex

Comparison between New test sample and “IDR” sample (500 GeV, w/ IP smearing)



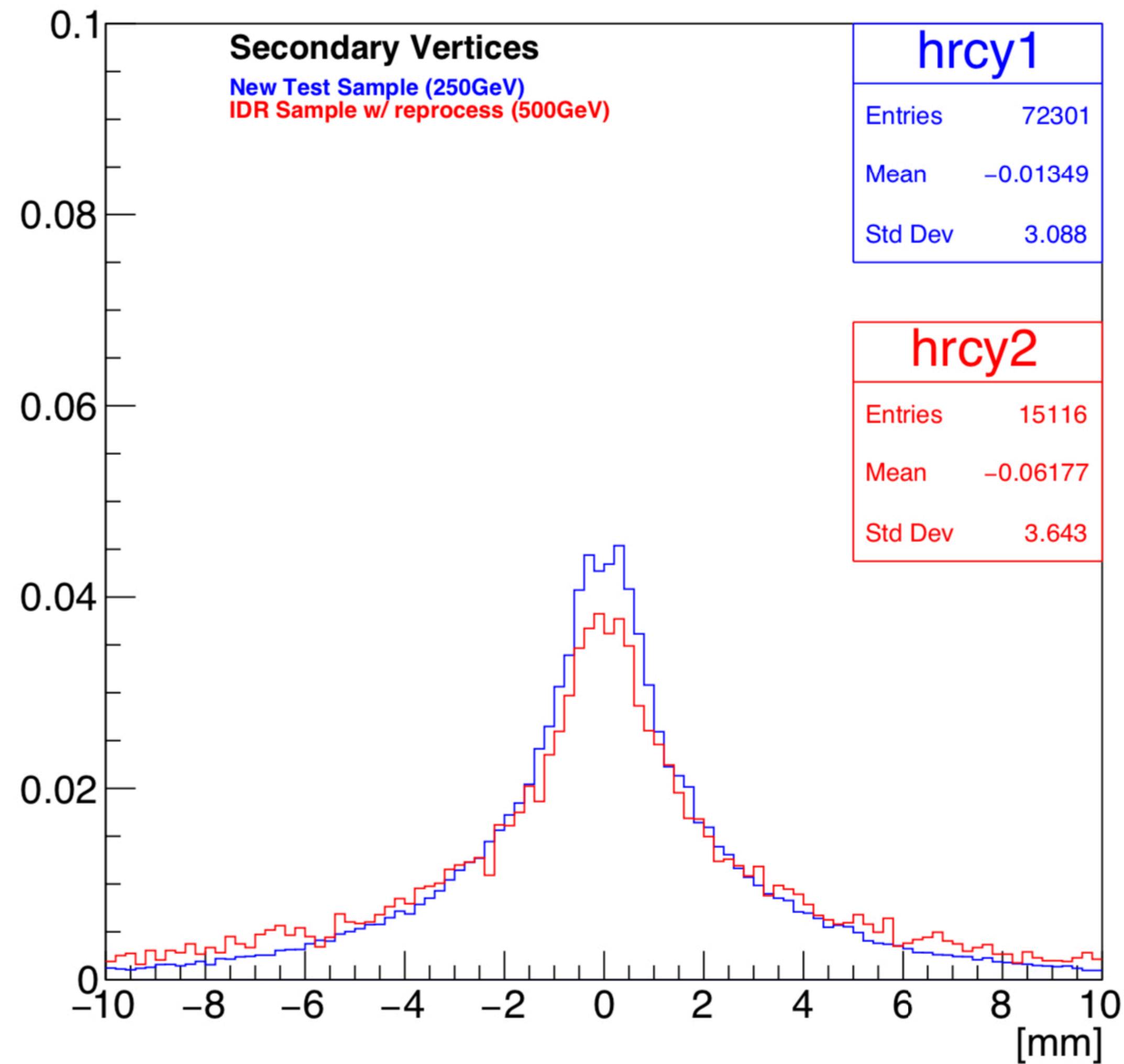
Secondary Vertex : x-position



Blue : New test sample

Red : IDR sample w/ reprocess (500 GeV, w/
IP smearing)

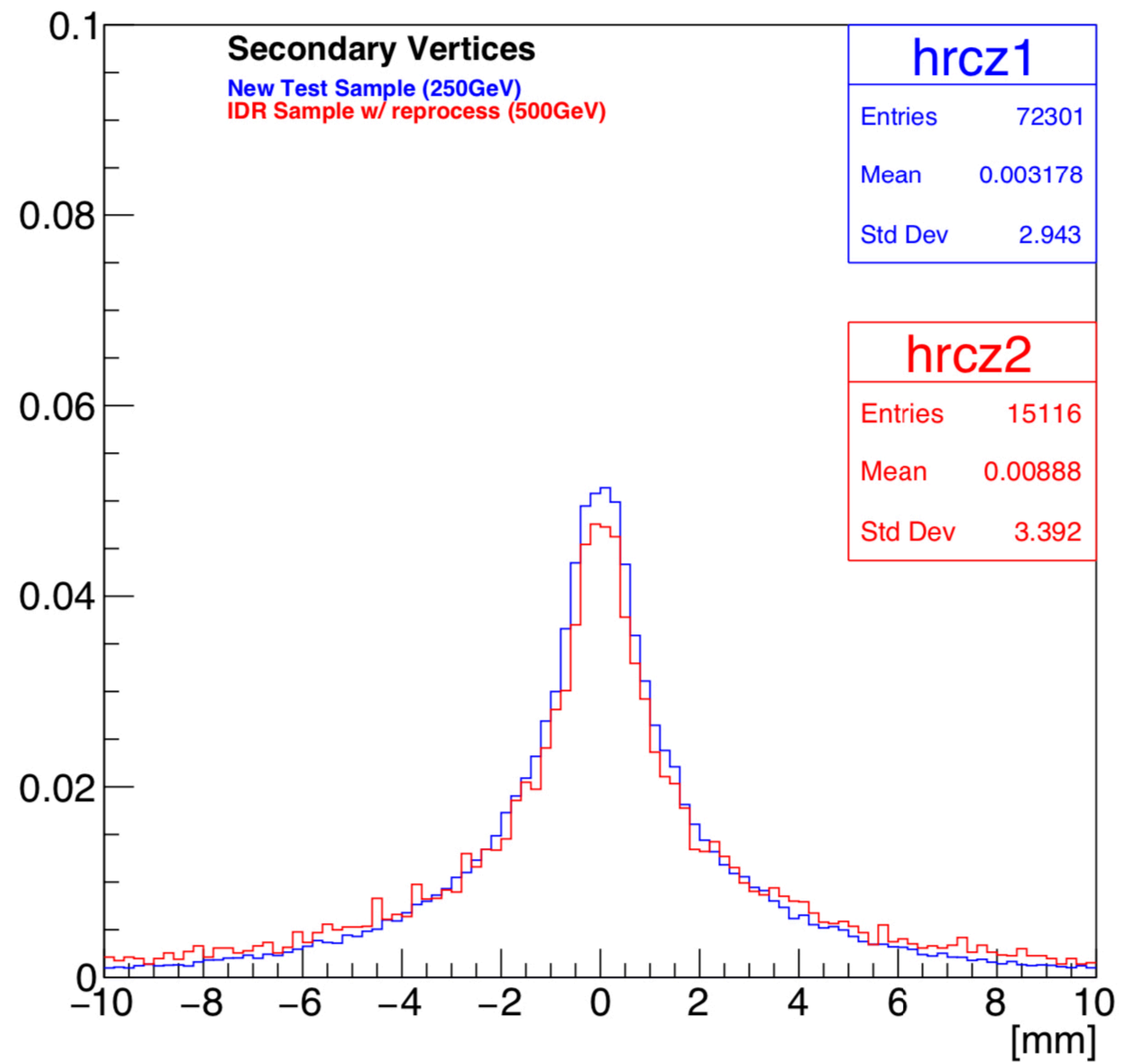
Secondary Vertex : y-position



Blue : New test sample

Red : IDR sample w/ reprocess (500 GeV, w/
IP smearing)

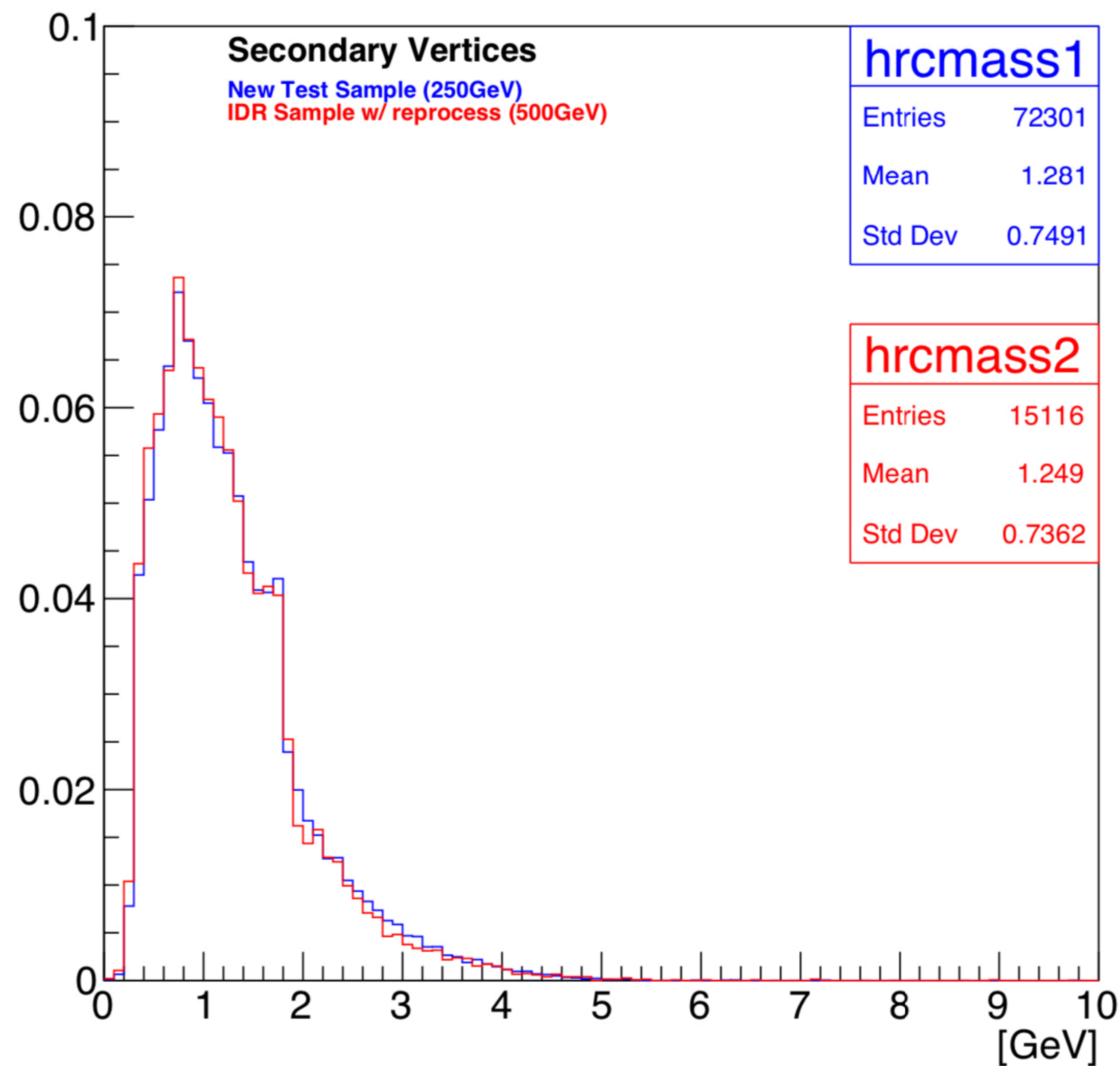
Secondary Vertex : z-position



Blue : New test sample

Red : IDR sample w/ reprocess (500 GeV, w/
IP smearing)

Secondary Vertex : Invariant mass of charged tracks

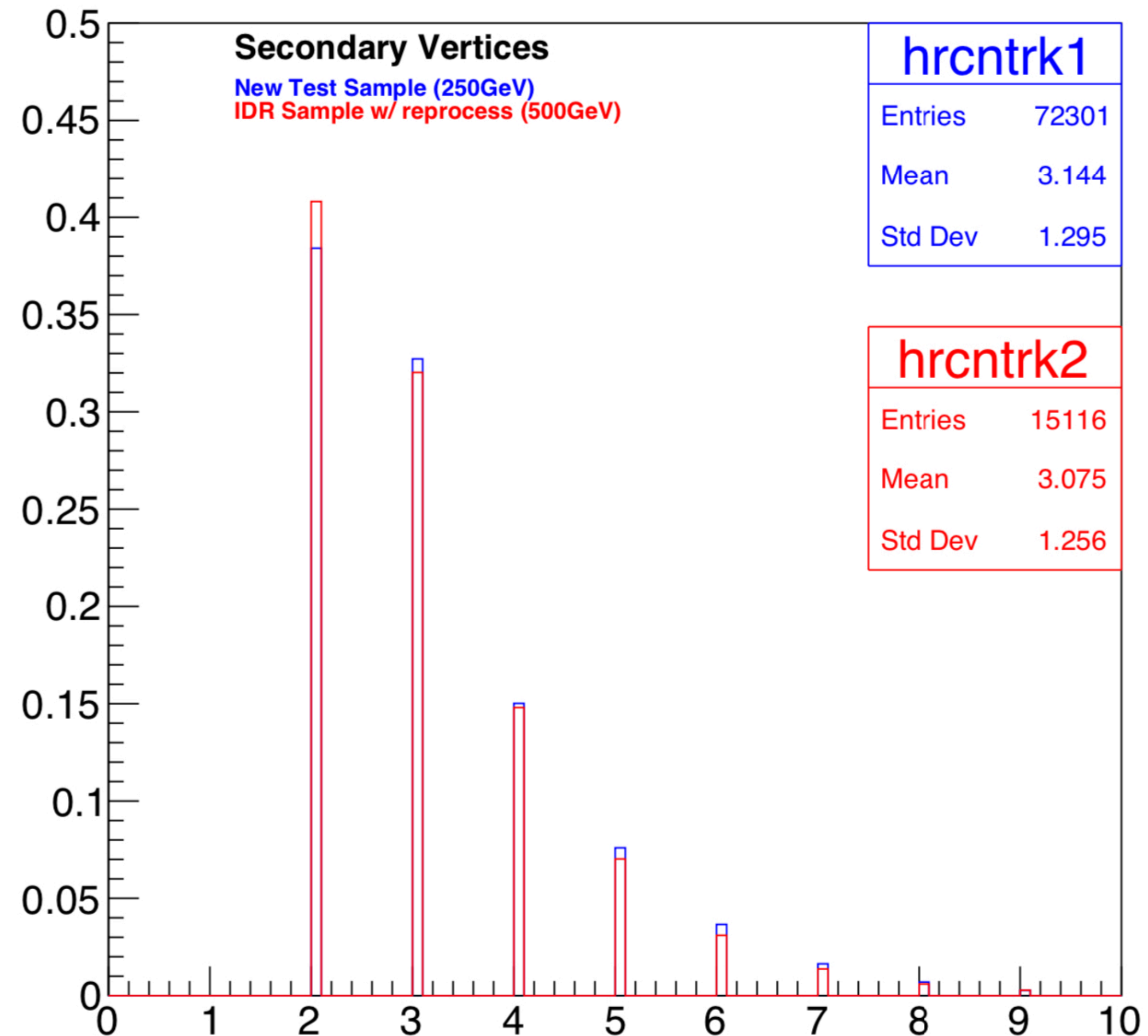


Blue : New test sample

Red : IDR sample w/ reprocess (500 GeV, w/
IP smearing)

No clear difference

Secondary Vertex : # of tracks

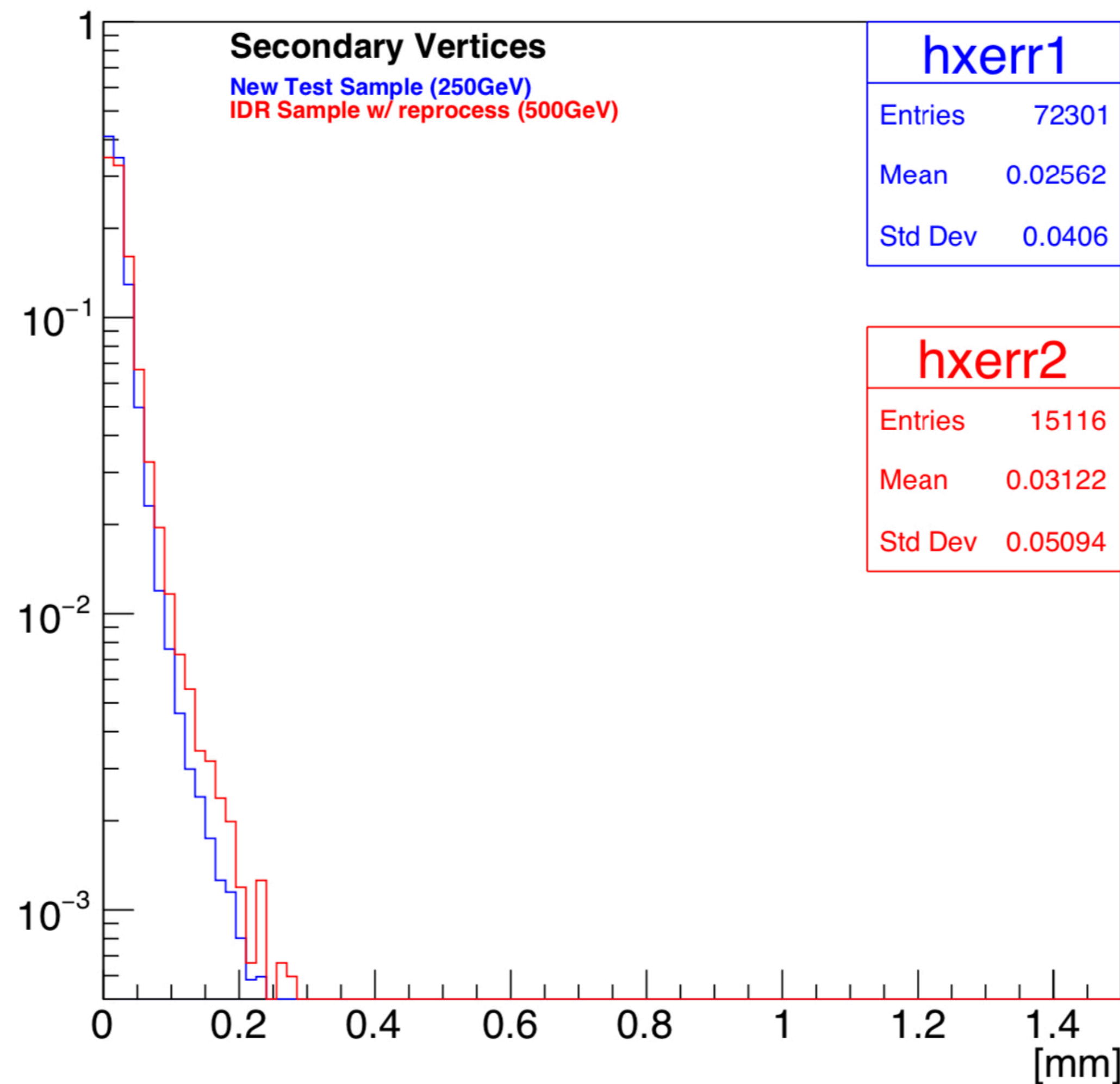


Blue : New test sample

Red : IDR sample w/ reprocess (500 GeV, w/
IP smearing)

No clear sign of problems

Secondary Vertex : x-position error from vtx fitting



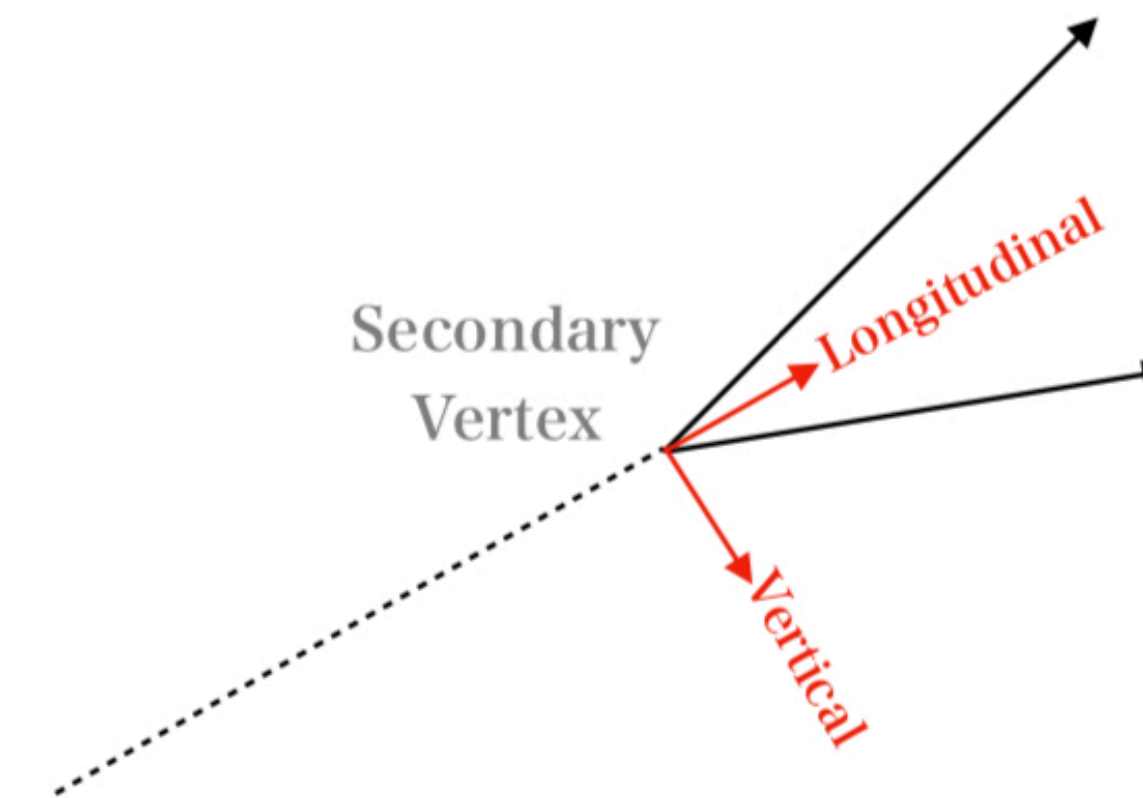
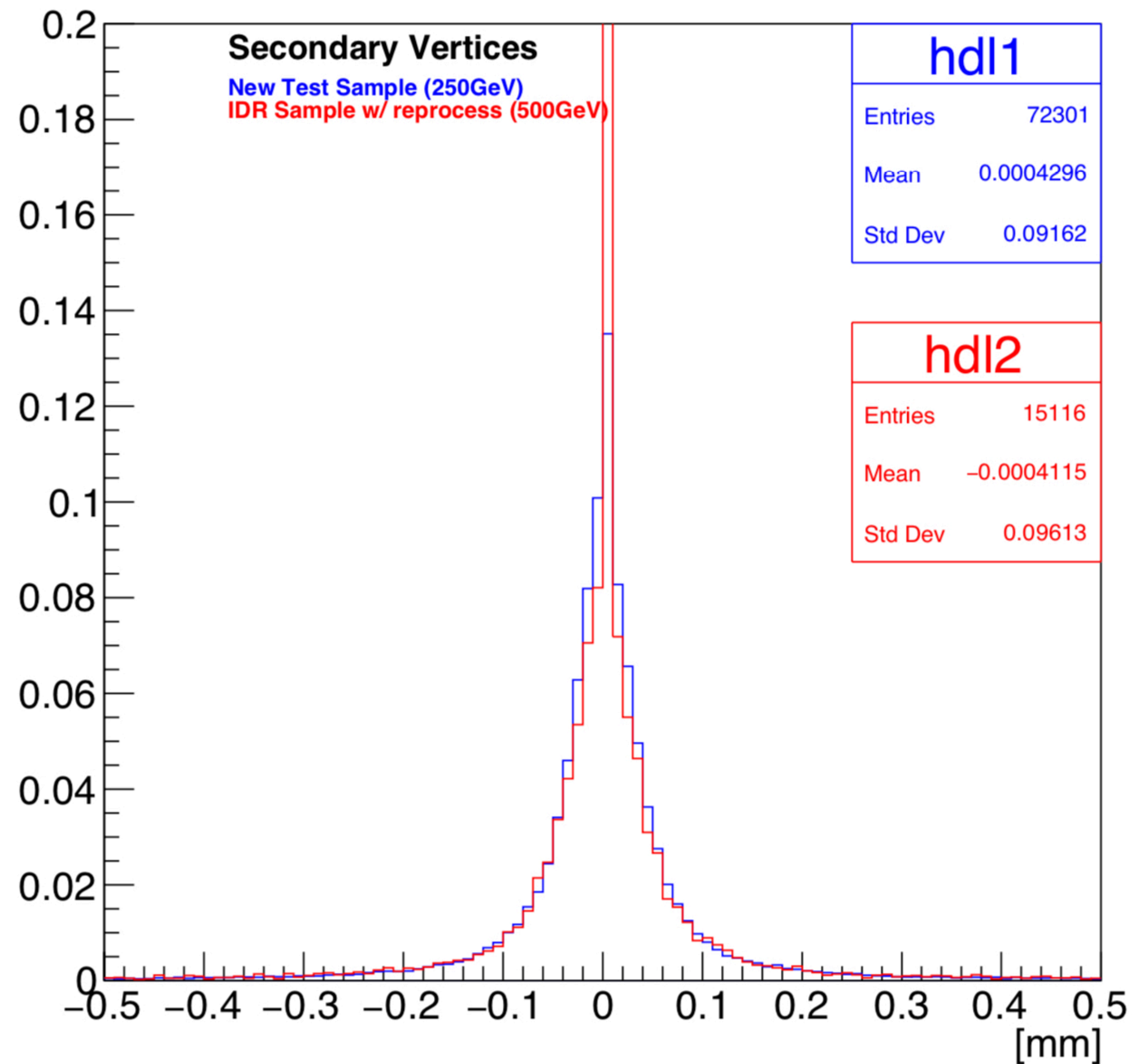
Blue : New test sample

Red : IDR sample w/ reprocess (500 GeV, w/ IP smearing)

See backup for y and z.

No clear sign of problems

Secondary Vertex : longitudinal resolution

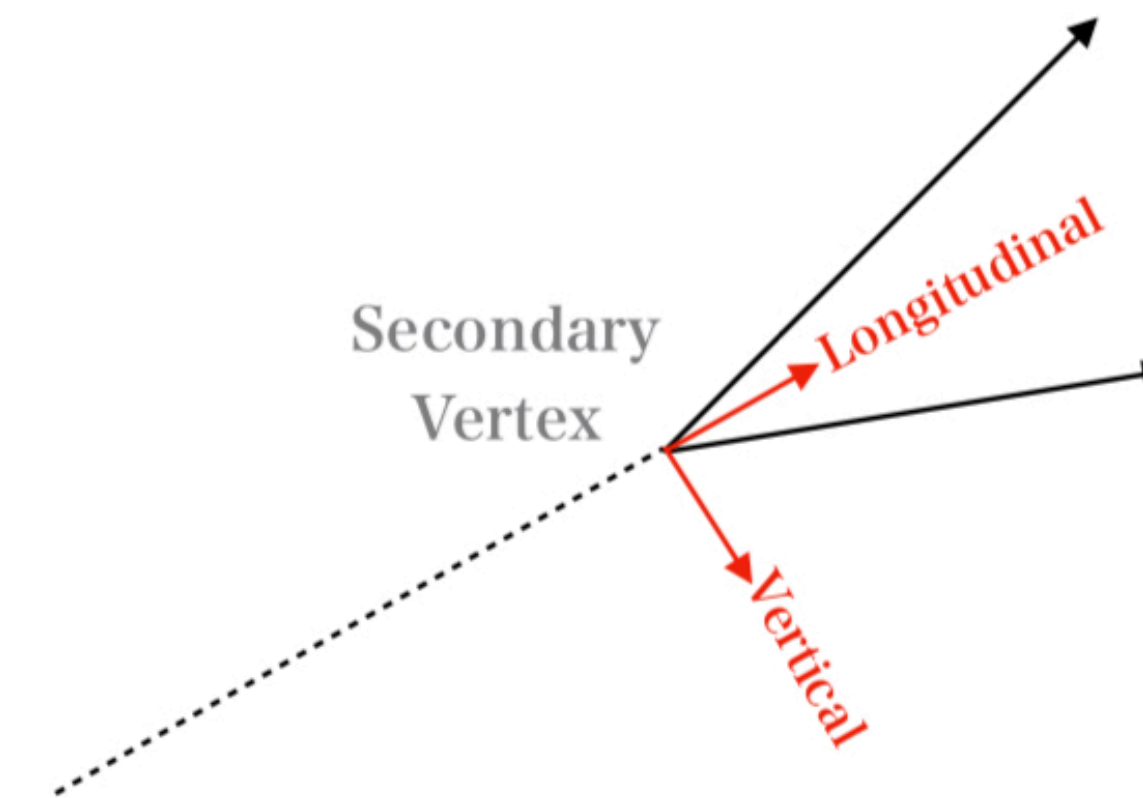
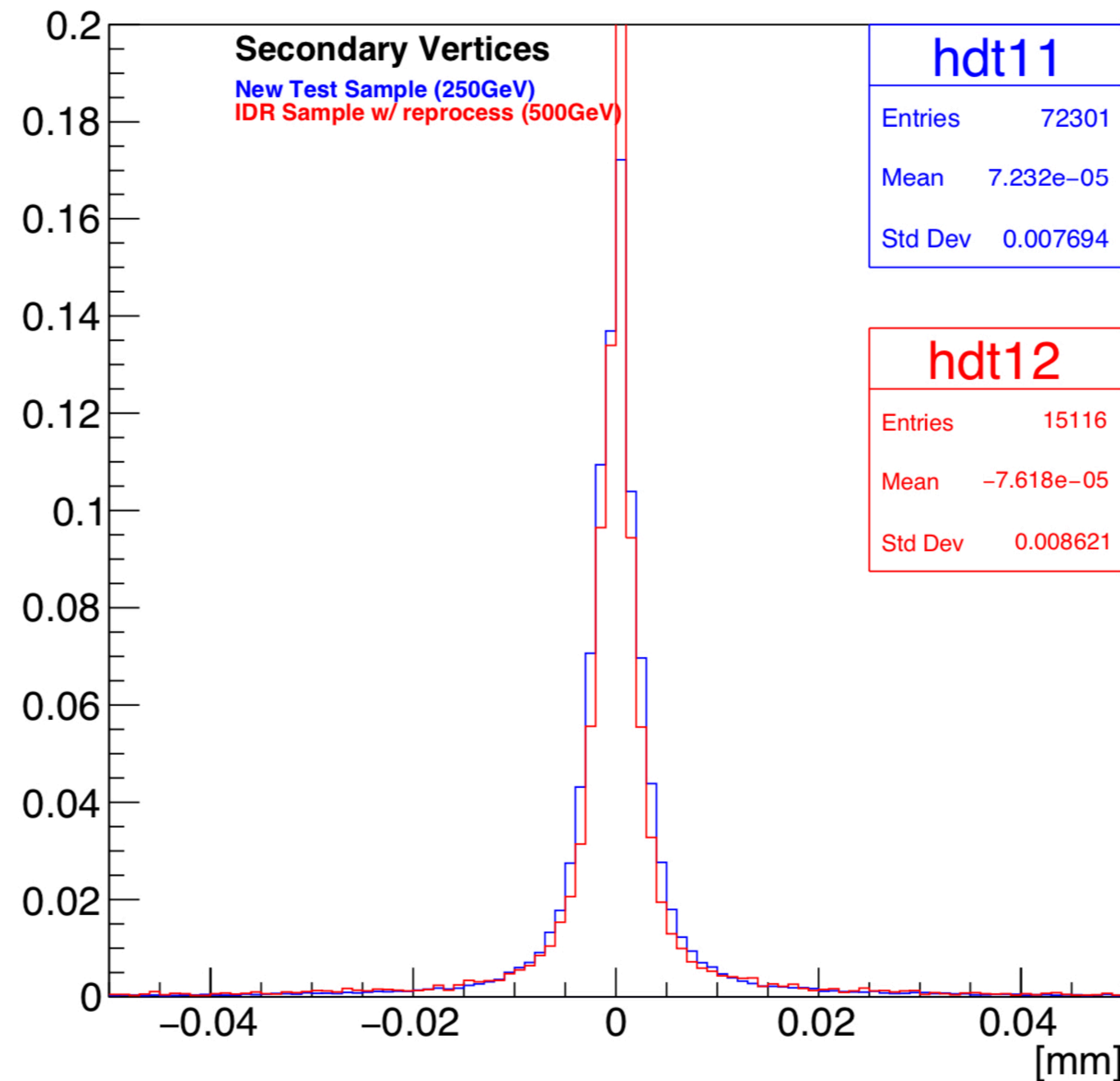


Blue : New test sample

Red : IDR sample w/ reprocess (500 GeV, w/ IP smearing)

No clear sign of problems

Secondary Vertex : Transverse resolution



Blue : New test sample

Red : IDR sample w/ reprocess (500 GeV, w/ IP smearing)

No clear sign of problems